

AD-A243 722



2

NAVAL POSTGRADUATE SCHOOL
Monterey, California

DTIC
ELECTED
DEC 30 1991
S D D B



THESIS

CONSTRUCTION AND TESTING OF AN 80C86 BASED
COMMUNICATIONS CONTROLLER FOR THE PETITE
AMATEUR NAVY SATELLITE (PANSAT)

by

Stephen M. Tobin

December, 1990

Thesis Advisor:

Mitchell L. Cotton

Approved for public release; distribution is unlimited.

91-19135



91 1227-007

UNCLASSIFIED

SECURITY CLASSIFICATION OF THIS PAGE

REPORT DOCUMENTATION PAGE

Form Approved
OMB No. 0704-0188

1a REPORT SECURITY CLASSIFICATION UNCLASSIFIED		1b. RESTRICTIVE MARKINGS	
2a. SECURITY CLASSIFICATION AUTHORITY		3. DISTRIBUTION/AVAILABILITY OF REPORT Distribution Statement A	
2b. DECLASSIFICATION/DOWNGRADING SCHEDULE			
4. PERFORMING ORGANIZATION REPORT NUMBER(S) Naval Postgraduate School		5. MONITORING ORGANIZATION REPORT NUMBER(S) Naval Postgraduate School	
6a. NAME OF PERFORMING ORGANIZATION	6b. OFFICE SYMBOL (If applicable) Code 33	7a. NAME OF MONITORING ORGANIZATION	
6c. ADDRESS (City, State, and ZIP Code) Monterey, California 93943-5000		7b. ADDRESS (City, State, and ZIP Code) Monterey, California 93943-5000	
8a. NAME OF FUNDING/SPONSORING ORGANIZATION	8b. OFFICE SYMBOL (If applicable)	9. PROCUREMENT INSTRUMENT IDENTIFICATION NUMBER	
8c. ADDRESS (City, State, and ZIP Code)		10. SOURCE OF FUNDING NUMBERS	
		PROGRAM ELEMENT NO.	PROJECT NO.
		TASK NO.	WORK UNIT ACCESSION NO.
11. TITLE (Include Security Classification) CONSTRUCTION AND TESTING OF AN 80C86 BASED COMMUNICATIONS CONTROLLER FOR THE PETITE AMATEUR NAVY SATELLITE (PANSAT)			
12. PERSONAL AUTHOR(S) Tobin, Stephen M.			
13a. TYPE OF REPORT Master's Thesis	13b. TIME COVERED FROM _____ TO _____	14. DATE OF REPORT (Year, Month, Day) December 1990	15. PAGE COUNT 105
16. SUPPLEMENTARY NOTATION The views expressed in this thesis are those of the author and do not reflect the official policy or position of the Department of Defense or the U.S. Government.			
17. COSATI CODES		18. SUBJECT TERMS (Continue on reverse if necessary and identify by block number) communications, satellite microprocessors, satellite	
FIELD	GROUP	SUB-GROUP	
19. ABSTRACT (Continue on reverse if necessary and identify by block number) This thesis describes the testing of a prototype of a satellite computer communications controller, based on the 80C86 microprocessor, which is to be placed on the Petite Amateur Navy Satellite (PANSAT) for launch in 1993 on a two year mission. First, the background of the justification for PANSAT is described. PANSAT will serve primarily as an inexpensive store-and-forward orbiting "mailbox", and secondarily it will serve as a teaching and learning vehicle for NPS faculty and students. Then there are reviews of the requirements and design concepts involved in the initial paper design by a previous thesis student. A reliability analysis is done, validating the reliability of the design. Finally, concepts considered in the wire-wrapped prototype construction are explained, followed by an extensive description of initial circuit testing and development of various machine language circuit test programs.			
20. DISTRIBUTION/AVAILABILITY OF ABSTRACT <input checked="" type="checkbox"/> UNCLASSIFIED/UNLIMITED <input type="checkbox"/> SAME AS RPT <input type="checkbox"/> DTIC USERS		21. ABSTRACT SECURITY CLASSIFICATION Unclassified	
22a. NAME OF RESPONSIBLE INDIVIDUAL Mitchell L. Cotton		22b. TELEPHONE (Include Area Code) (408) 646-2377	22c. OFFICE SYMBOL Code EC/Cc

Approved for public release; distribution is unlimited.

Construction and Testing of an 80C86 Based
Communications Controller for the Petite
Amateur Navy Satellite (PANSAT)

by

Stephen M. Tobin
Captain, United States Army
B.S., United States Military Academy, 1980

Submitted in partial fulfillment
of the requirements for the degree of

MASTER OF SCIENCE IN ENGINEERING SCIENCE (COMPUTER SYSTEMS)

from the

NAVAL POSTGRADUATE SCHOOL
December 1990

Author:

Stephen M. Tobin
Stephen M. Tobin

Approved by:

Mitchell L. Cotton
Mitchell L. Cotton, Thesis Advisor

Chin-Hwa Lee
Chin-Hwa Lee, Second Reader

Michael A. Morgan
Michael A. Morgan, Chairman
Department of Electrical and Computer Engineering

ABSTRACT

This thesis describes the testing of a prototype of a satellite computer communications controller, based on the 80C86 microprocessor, which is to be placed on the Petite Amateur Navy Satellite (PANSAT) for launch in 1993 on a two year mission. First, the background of the justification for PANSAT is described. PANSAT will serve primarily as an inexpensive store-and-forward orbiting "mailbox", and secondarily it will serve as a teaching and learning vehicle for NPS faculty and students. Then there are reviews of the requirements and design concepts involved in the initial paper design by a previous thesis student. A reliability analysis is done, validating the reliability of the design. Finally, concepts considered in the wire-wrapped prototype construction are explained, followed by an extensive description of initial circuit testing and development of various machine language circuit test programs.

Accession For	
NTIS CP421	<input checked="" type="checkbox"/>
DTIC DA2	<input type="checkbox"/>
Unclassified	<input type="checkbox"/>
Justification	
By	
Distribution	
Analogy Code	
Dist	Approved by Sp. Ed.
A-1	

Approved by Sp. Ed.

TABLE OF CONTENTS

I. INTRODUCTION.....	1
A. PURPOSE AND SCOPE OF THESIS.....	1
B. PANSAT BACKGROUND.....	3
1. PANSAT Concept.....	3
2. Mission and Objectives.....	4
3. PANSAT Design.....	5
a. Orbit.....	5
b. Size.....	5
c. Stabilization.....	6
d. Communications.....	7
e. Power.....	9
f. Durability.....	10
g. Lifetime.....	10
C. PANSAT COMPUTER FUNCTIONS.....	10
1. Communications.....	10
2. Telemetry.....	11
3. Housekeeping.....	11
4. Transmitter Control.....	11
D. DESIGN CONSTRAINTS AND CONSIDERATIONS.....	12
1. Commonality.....	14
2. Upward Compatibility.....	14
3. Reliability.....	15

4.	Estimate of System Reliability.....	16
5.	Radiation Hardening.....	21
6.	Environment.....	21
a.	Launch.....	21
b.	Orbit.....	21
7.	Power.....	22
8.	Communications Protocol.....	22
a.	Error Detection.....	22
b.	Error Correction.....	23
E.	PREVIOUS FLIGHT DESIGNS.....	23
1.	Uo SAT-2.....	24
2.	Uo SAT-D.....	25
3.	FO-12.....	25
II.	ORIGINAL DFSIGN CHOICES/PROTOTYPE CHANGES.....	26
A.	PROCESSOR SELECTED.....	26
B.	PROCESSOR MODE.....	26
C.	BUS DEMULTIPLEXING.....	26
D.	CLOCK AND PERIPHERALS.....	27
1.	Analog to Digital Converter.....	27
2.	Parallel Port.....	27
3.	HDLC.....	27
4.	Timer.....	27
5.	Interrupt Controller.....	28
6.	I/O Device Chip Selection.....	28
7.	Clock.....	28
8.	I/O Device Timing.....	28

9. Reset.....	28
10. Miscellaneous Changes.....	28
E. MEMORY SYSTEM.....	29
1. (E)PROM.....	29
2. Vital RAM.....	29
3. Bulk RAM.....	30
F. LOGIC DEVICE FAMILY SELECTION.....	30
1. CMOS v. TTL.....	30
a. Speed.....	30
b. Power.....	32
c. Noise Immunity.....	32
2. Compatibility.....	33
3. MIL-SPECS.....	33
III. WIRE-WRAP CONSTRUCTION AND TESTING.....	34
A. LAYOUT.....	34
1. Wire Size(s).....	34
2. Heat Dissipation.....	34
3. Component Placement to Minimize Wire Length..	34
a. Stray Capacitance.....	36
b. Signal Degradation and Power Drop.....	36
c. Propagation Delay.....	37
4. Filter Capacitors.....	37
B. CMOS POTENTIAL PROBLEMS/CONSIDERATIONS.....	38
1. Unused Inputs.....	38
2. Latch-up.....	39

3. Pull up resistors.....	41
4. Fan out.....	41
5. Fast Rise-times and Harmonics.....	42
C. Incremental Testing.....	43
1. Clock and Clock Frequency Divider.....	43
2. CPU, EPROM, Latches, and Data Transceivers...	43
3. Memory.....	45
4. The Need for a Monitor.....	49
5. Timer.....	50
6. Interrupt Controller.....	52
7. Serial Communications Controller (SCC).....	60
IV. RECOMMENDATIONS FOR FURTHER WORK.....	65
A. WRITE A CHARACTER TO THE CRT.....	65
B. INSTALL HOST-TO-TARGET MONITOR PROGRAM.....	65
C. WRITE OPERATING SYSTEM BOOTSTRAP KERNEL.....	65
D. IMPLEMENT AX.25 PROTOCOL.....	66
E. IMPLEMENT RESET.....	66
F. IDENTIFY OTHER REQUIREMENTS AND BEGIN HARDWARE OR SOFTWARE MODIFICATION.....	66
APPENDIX A. 8086 INSTRUCTION SET.....	67
APPENDIX B. INITIAL CIRCUIT TEST PROGRAM.....	69
APPENDIX C. INITIAL MEMORY TEST PROGRAM.....	70
APPENDIX D. M/IO* TEST PROGRAM.....	71
APPENDIX E. INITIAL 82C54 TIMER TEST PROGRAM.....	72
APPENDIX F. INTRPT CNTRLR TEST PROGRAM: INCREMENT 1.....	74
APPENDIX G. INTRPT CNTRLR TEST PROGRAM: INCREMENT 2.....	76

APPENDIX H. INTRPT CNTRLR TEST PROGRAM: INCREMENT 3.....	81
APPENDIX I. SERIAL COMMUNICATIONS CONTROLLER TEST PGM...	87
APPENDIX J. LIST OF COMPONENTS.....	90
LIST OF REFERENCES.....	91
INITIAL DISTRIBUTION LIST.....	94

LIST OF FIGURES

Figure 1	Pansat Size and Structure [Ref. 5].....	6
Figure 2	Portion of Orbit in Sunlight.....	8
Figure 3	Computer System Diagram.....	13
Figure 4	Typical System Reliability Function [Ref. 12].....	17
Figure 5	"Bathtub Curve" [Ref. 12].....	19
Figure 6	CMOS v. TTL Relative Power Consumption & Speed [Ref. 19].....	31
Figure 7	CMOS Power Dissipation v. Frequency [Ref. 19].....	32
Figure 8	Prototype Board Layout.....	35
Figure 9	CMOS AND Gate [Ref. 19].....	39
Figure 10	CMOS Latch-up Process [Ref. 23].....	40
Figure 11	Clock Circuit Schematic.....	44
Figure 12	Loop Test Schematic--Clock and CPU.....	46
Figure 13	Loop Test Schematic--EPROM Only.....	47
Figure 14	Complete Circuit Schematic--Memory.....	48
Figure 15	Memory/IO Test Schematic.....	51
Figure 16	Countdown Timer Test Schematic.....	55
Figure 17	Interrupt Controller Test Schematic.....	57
Figure 18	Interrupt Controller Test--Increment 2.....	60
Figure 19	Complete Circuit Schematic--CPU.....	62
Figure 20	Complete Circuit Schematic--Peripherals....	63

I. INTRODUCTION

This thesis builds upon a principal previous thesis [Ref. 1]. That previous author's purpose was to derive an initial design for a small, inexpensive, reliable, on-board, satellite communications controller for the Petite Amateur Navy Satellite (PANSAT). Hence, much of the form and content of this introduction comes from that author's thesis.

A. PURPOSE AND SCOPE OF THESIS

The purpose of this effort was to verify the utility and validity of the cited paper design of the on-board processor for the Petite Amateur Navy Satellite (PANSAT). The establishment of the processor requirements and the processor design were the subjects of that previous thesis [Ref. 1]. The requirement was to design and build a small, inexpensive, and reliable computer controller with enough memory and capability to act as a store-and-forward "mailbox" for amateur packet-radio messages using the AX.25 protocol. In addition, of course, the controller had to be able to withstand the extremes of radiation, heat, and cold in outer space. The design was a challenging task.

This current thesis is a continuation of only a portion of the required steps towards implementation of the actual flight-ready processor based on the initial design. This

effort concentrated on the building of a wire-wrapped breadboard prototype and the incremental testing of the hardware using relatively simple machine language programs. These programs were written to incrementally test some of the basic operations which will be required of the controller in its final flight-ready form. Correct operation of all the system's components within the system has been verified.

A 100 MHz dual-trace oscilloscope was the tool used to test for the presence of predicted signals. As the hardware and software of the system incrementally grew in complexity, it became increasingly difficult to verify correct circuit operation with just the oscilloscope, e.g., see the discussion of the third incremental test of the interrupt controller. Was the problem with the oscilloscope not being able to lock on the increasingly longer period, less stable signal, or was the problem with the program's complexity exceeding the circuit's capabilities? A better monitoring system will have to be constructed to carry on from this point. This possible (unlikely) circuit failure could indicate the necessity of some sort of redesign, assuming no flaws in the components or the prototype construction itself. Once a keyboard, monitor, and assembler/compiler are constructed for the system, the next step will be to find out if the system is in fact operating at the edge of its design parameters, and if so, what can be done about it.

B. PANSAT BACKGROUND

The Petite Amateur Navy Satellite (PANSAT) is a small, simple, and inexpensive satellite currently being designed at the Naval Postgraduate School. It is a precursor to the NPS ORION satellite project.

1. PANSAT Concept

PANSAT is intended to be a space-based communications experiment that provides students with hands-on experience in satellite design and operations. It will accomplish three objectives. First, it will serve as an educational tool for NPS officer students, offering them experience in satellite design and operations. Second, it will provide world-wide digital communications using spread spectrum in the amateur band. Third, it will serve as a low-cost, space-based platform for small experiments. [Ref. 2:p. 2]

Additionally, it is an important milestone in achieving for the Space Systems Academic group its ultimate goal of producing the ORION satellite [Ref. 3]. It is a simpler and less capable satellite than ORION. Because PANSAT is less than half of ORION's size and is not attitude stabilized it can be produced for a fraction of the cost of the final version of ORION. Simplicity will help minimize the risks inherent in a first design. Simplicity will also result in reduced cost [Ref. 1:p. 1]. A tentative launch date has been set for 1993 [Ref. 4].

2. Mission and Objectives

The primary mission of PANSAT is to conduct a space-based communications experiment which will provide students with experience in design and operation of such a system. The desired implementation is a store-and-forward message system. In effect, the satellite would be a (delayed) transponder or mailbox. This would allow an authorized user to send a message to the satellite while the satellite was overhead. At a later time, another authorized user could retrieve the message. Outdated or retrieved messages could be (and would eventually have to be) deleted [Ref. 1:pp. 1-2].

In addition, several secondary missions are being considered if volumes and weights permit. These would probably require various analog or digital sensors which would amass various data, e.g., solar cell efficiency or degradation data. This telemetry data could then be periodically collected on-board by the computer and stored as messages. Various programs could be loaded into the satellite processor from the ground, and then tested. This could give NPS students, and others, experience in writing software for satellite control or experiments. One could also write monitor programs to monitor memory errors over time, or to monitor power usage by memory and processor components over time. This would allow students to evaluate the effects on memory circuits and/or semiconductor

components of exposure to increased radiation and a harsh environment [Ref. 1:p. 2].

3. PANSAT Design

The following are the working design constraints that impact on the processor system design.

a. Orbit

The first PANSAT is planned for launch from the space shuttle in a Get Away Special (GAS) canister or expendable launch vehicle. This constrains the satellite to a typical low earth orbit of approximately 480 km inclined at 28.5 degrees [Ref. 5:p. 2]. The actual orbit will depend on shuttle parameters of the particular mission that launches the PANSAT. Typical orbits have a 90 minute period. The orbit will also determine specific communication opportunities with the satellite. A typical orbit will provide only two or three, greater than ten-minute communications windows per day at the latitude of NPS for any particular ground station [Ref. 6:pp. 7-10].

b. Size

The Get Away Special canister size limits the physical size of the satellite. If a regular size canister is used, this limits satellite size to approximately 19 inches in diameter. Working within these limits, an octagonal cross section design is planned to maximize solar collector area. (See Figure 1.) The satellite volume reserved for the processor and its memory is also shown in

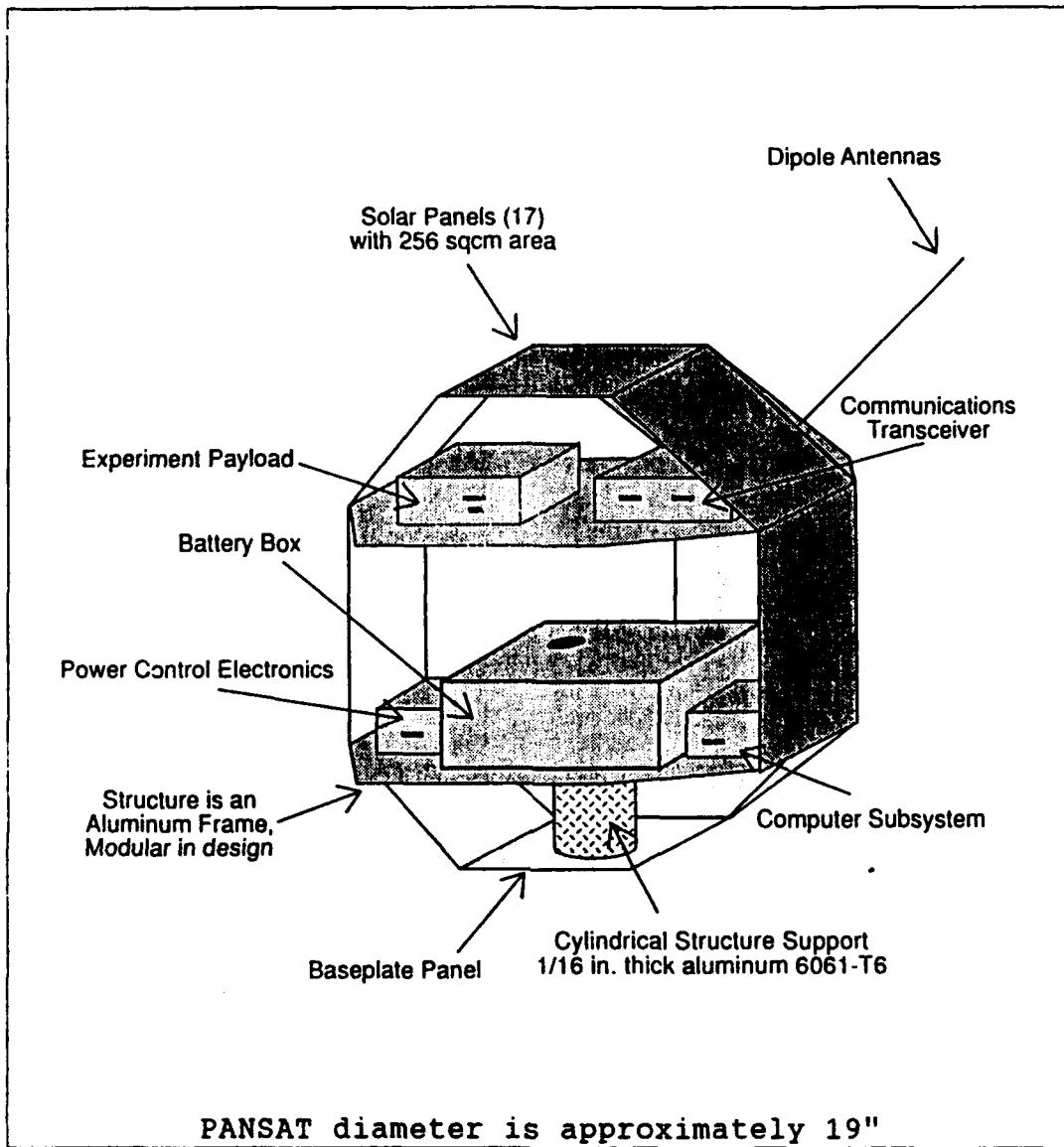


Figure 1. Pansat Size and Structure [Ref. 5]

the figure.

c. Stabilization

The PANSAT will not be stabilized and will not have any station keeping ability. This means that the processor does not require the capability to monitor any attitude sensors or perform any stabilization calculations. Another

advantage to the lack of stabilization in relation to the processor is the potential to leaven the effect of solar heating on the daylight portion of the orbit which constitutes 61.20% of the total equatorial orbit based on strictly line of sight calculations with an earth radius of 6.4×10^6 meters and a satellite elevation of 480 kilometers. (See Figure 2, on the next page.) Refraction due to the atmosphere will undoubtedly extend that percentage somewhat. Lack of stabilization will dictate the use of an omnidirectional antenna(s) which will have a negative effect on the signal-to-noise ratio and on the communications power budget. These problems will be primary concerns of the communications and power supply designers.

d. Communications

The radio communications link with the PANSAT is currently planned to have a 437.25 MHz center frequency with a 960 kHz bandwidth. It will utilize the AX.25 amateur packet-radio communications protocol in half-duplex mode at 1200 bps [Ref. 5:p 3]. The reason for the low 1200 bps data rate is two-fold. First, a low data rate will conserve power on the satellite because less bandwidth is required. Second, it will reduce the probability of bit error thereby possibly making forward error correction (FEC) and its attendant hardware and/or software less important and possibly not required.

$$((2 \times 21.53) + 180)/360 \times 100 = 63.29\% \text{ in sunlight}$$

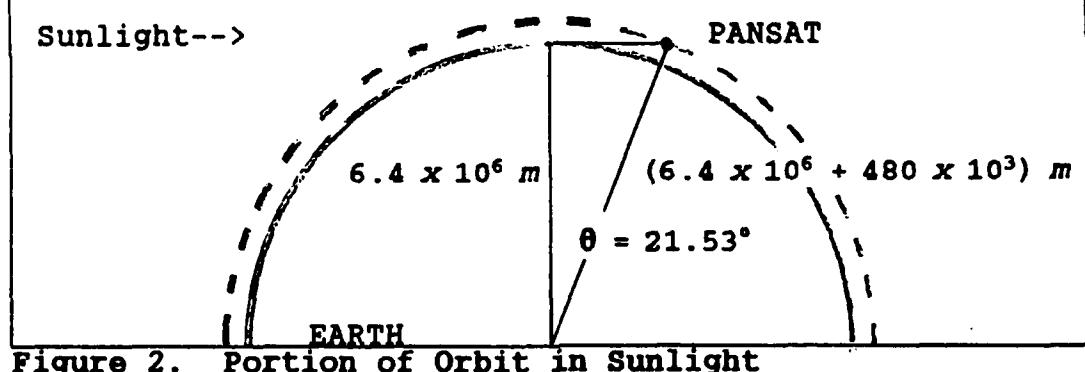


Figure 2. Portion of Orbit in Sunlight

The AX.25 protocol utilizes automatic repeat request (ARQ) at the frame level for error correction. With too high a bit error rate (BER) due to a high data transmission rate this could be too time consuming. But with only a 10 minute or less communications window there is a tradeoff with the desire to keep the data transmission rate

low to reduce the BER and the need to get all the data transmitted during the short window. There is room here for further data transmission rate optimization studies which is primarily dependent on the signal-to-noise (S/N) ratio of the PANSAT/ground antenna/transmitter/receiver system and its chosen modulation method. [Ref. 7:p. 28]

The current communications subsystem design forecasts a bit error rate of 10^{-5} [Ref. 6:p. 19]. This is a probability of one character being incorrect every 2.6 pages. (A page is assumed to be $60 \times 80 = 4800$ bytes = 38400 bits.) Since there will be a maximum amount of available RAM for telemetry/messages of about 800 kilobytes, it will take about $800 \text{ kilobytes} / 1200 \text{ sec.} = 90$ minutes to completely load or unload the RAM. But any message of a page or less (about 4800 bytes) will only take about 4 seconds or less to transmit or receive. Most messages will surely be on the order of a page or less.

e. Power

The satellite will be powered by an array of 15 volt solar cells mounted on the exterior. These will charge two 10.5 volt lead-acid batteries in parallel. The batteries each consist of five 2.1 volt, 5 ampere-hour cells. The batteries are required, of course, for the eclipsed portions of the orbit. A breadboard version of the power system has been designed and constructed. The nominal power requirements of the PANSAT are not yet known because not all

the systems have been designed and/or built but the breadboarded power system design estimated that 11.0 watts average power will be required, of which the processor's share is 2.6 watts 100% of the time. [Ref. 8]

f. Durability

The satellite will be subjected to high vibration during launch and orbital injection. The overall root mean squared vibration level is 12.9 g's for 40 seconds [Ref. 9:p. 57]. The processor must be able to withstand these stresses without failure.

g. Lifetime

The processor must be able to function properly during the satellite's design lifetime of one and one half years. The design should be such that system failure can be avoided. If a fault occurs, the design should minimize the impact on the mission by redundancy (appropriate to the relative simplicity of the satellite) or by allowing the processor to work around the fault. [Ref. 1:p. 6]

C. PANSAT COMPUTER FUNCTIONS

The following functions are to be performed by the processor:

1. Communications

The satellite will act as an orbital store-and-forward message service. The satellite will be capable of receiving messages via a communications link, storing the

messages, and transmitting them upon request. There should be a way for the processor to transmit a list of its current messages, upon request. Also, messages will have to be periodically erased to free up memory space.

2. Telemetry

The processor may store telemetry data from on-board sensors and the satellite will transmit the data upon request.

3. Housekeeping

The processor must manage housekeeping functions in support of the mission functions. These housekeeping functions could include, but are not limited to:

- a. Power management and monitoring of power supply voltage, battery charging current, and battery current draw.
- b. Generation and formatting of status messages.
- c. Reception, decoding, and execution of commands from the ground control station.
- d. On-board fault detection and recovery. (Message fault detection and recovery is a function of the AX.25 protocol.)
- e. Ability to update or change programming.

4. Transmitter Control

A major concern for getting the PANSAT design approved for launch is demonstrating positive control over the transmitter. If the satellite has a malfunction, there must still exist means to secure the transmitter from the

ground station. Legally, telecommand capability is necessary: "...to turn off a malfunctioning transmitter that might conceivably cause harmful interference to important radio services worldwide." [Ref. 10:p. 12-2]

Transmitter control will be a joint responsibility between the processor and the communications subsystem. During normal operation, the processor will turn the transmitter on and off, but if the processor fails during transmission, the communications subsystem must have a way to secure the transmitter. If the receiver and/or the serial communications controller and/or the processor or software fail with the transmitter keyed on so that the receiver has no way to secure the transmitter, a watchdog countdown timer is provided with the processor to time out and reset the processor, thereby securing the transmitter. Then, if the fault is not correctable, either from the ground or on the satellite, the transmitter is left turned off. Figure 3, on the next page, is the overall computer system diagram. It clearly shows the implementation of a watchdog timer to effect positive transmitter control.

D. DESIGN CONSTRAINTS AND CONSIDERATIONS

Other microprocessors or microcontrollers available in a low power, radiation hardened version could have been used for the initial design, e.g., the 8085, Z80, MC68000, 8096 (microcontroller), and others, but the 80C86 is a good choice

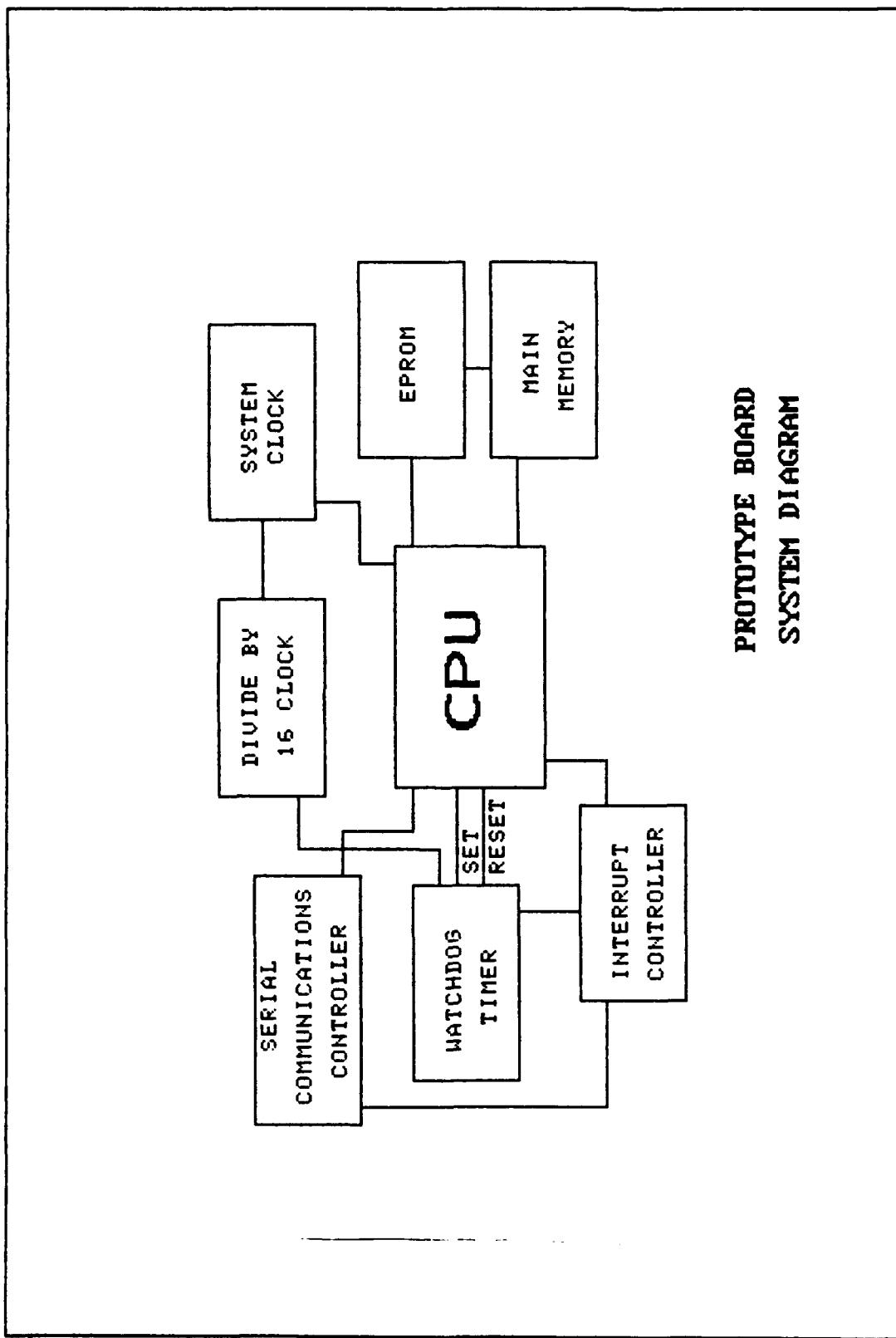


Figure 3. Computer System Diagram

because it is probably better known, with commonly available compilers, assemblers, and software. Most of the following items were considered in the paper design of the processor system in the predecessor's thesis [Ref. 1].

1. Commonality

The processor should be similar to one commonly available. This will simplify program development and allow increased educational benefits. Program development is simplified by the larger number of software packages (i.e., compilers and assemblers) available for a common processor. It is very desirable that the processor have high level language compilers available to allow programming the processor in C or an equivalent language. The educational benefit is enhanced by allowing students to develop a program on a ground-based computer. Once debugged and verified a program can be uploaded and tested on an actual satellite. The 80C86 microprocessor fits this consideration nicely.

2. Upward Compatibility

The PANSAT processor should be one which can be easily expanded to meet the greater demands of ORION. The 80C86 is a less powerful member of the Intel 80x86 family of microprocessors. A more powerful processor, e.g., the 80386, could be substituted for the 8086 with increased speed, memory addressing capability, and multi-processor configuration capability, without the need for much modification of existing software or support tools which will

have been developed and debugged for use in the PANSAT program.

3. Reliability

Reliability is one of the most important, if not the most important consideration in the design of a satellite-borne computer system because on-station satellite repair is so expensive. Computer system reliability is a function of design simplicity, operational requirements, the environment and its effect on durability, individual component reliability, and error detection and/or correction capability. Error detection and correction capability is a tradeoff with simplicity of design. The harsh effects of the space environment can be mollified by the use of radiation hardened parts, shielding, thermal control, and (for launch) shock absorbing and vibration dampening mounts. For the design of this simple system one can ensure component reliability by using less than state-of-the-art parts from a reputable company, such parts being well understood and tested with a reliability track record. This again argues for the use of a system based on a common processor like the 80C86 with its attendant memory and commonly used peripheral support chips.

The reference cited below lists some things a designer can incorporate into a spacecraft system to increase its reliability (only that portion of the list applying to the computer subsystem is shown):

- ...
 - Data communications
 - ...
 - Digital error detection and correction techniques
- Command and Control
 - Hardware testing of parity, illegal instruction, memory addresses
 - Sanity checks
 - Memory checksums
 - Task completion timed
 - Watchdog timers
 - Memory write protection
 - Reassemble and reload memory to map around the memory failures [Ref. 11:p. 342]

Some, or all of these could be used in the final design. The watchdog timer is already incorporated in the design.

4. Estimate of System Reliability [Ref. 12:p. 669-674]

To keep the system simple, there is minimal redundant circuitry. Partial protection from software failure is taken care of by the watchdog timer. The only accommodation to redundancy may be in the inclusion of a duplicate bootstrap EPROM. Will this system, as it stands, be reliable enough? As stated earlier, per diem and travel expenses are prohibitively costly for repairmen to do maintenance on a small, inexpensive low-earth orbit satellite such as PANSAT. However, it is possible and very easy to get a ballpark figure for the overall system reliability to assure oneself that the computer system will be reliable enough. The cited reference explains that reliability, as a function of time, $R(t)$, is simply the probability that the system still works

correctly at time t . The way this function could be derived is to build lots of systems and then plot the number of systems still working against time, t . Typically, the resulting graph will be an exponentially decreasing curve. See Figure 4.

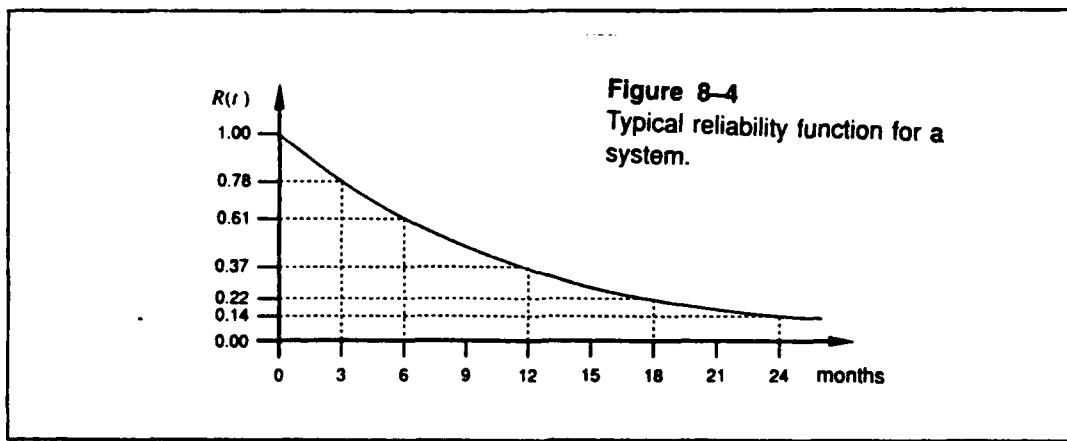


Figure 4. Typical System Reliability Function [Ref. 12]

However, it is impractical and expensive to derive the value for the failure rate by actually building many systems and testing them over a long period of real time. Instead, one takes the reliability information from the specification sheets for the system's individual components. Then one derives the overall system reliability from that information, using a simple mathematical model, to be described below.

Typically, reliability information for electronic components are available from the manufacturer in the form of a failure rate per unit time. This failure rate is usually

expressed by the Greek letter λ . This λ is determined by the manufacturer as follows:

$$\lambda = \frac{\text{number of chip failures}}{\text{number of chips tested} \cdot \text{number of hours tested}}. \quad (1)$$

Therefore, the reliability of a component can be expressed as

$$R(t) = e^{-\lambda t}. \quad (2)$$

Because the failure rates for electronic components are generally very small, these failure rates are often expressed in a scaled unit called a FIT where

$$1 \text{ FIT} = 1 \text{ failure}/10^9 \text{ hours}. \quad (3)$$

These component failure rates are usually not constant, however. They typically display a bathtub shaped curve when plotted against time. See the figure (Figure 5) on the next page.

The high failure rates during the infant mortality portion of the curve are usually eliminated by the manufacturer's burn-in procedure. If a component is going to fail due to improper or borderline manufacture, the defect should reveal itself early on. The manufacturer only ships those components which have survived this initial testing period. Most components never make it to the wear-out stage. The systems containing them typically become obsolete or

Figure 8-5
The "bathtub curve" for
electronic-component failure
rates.

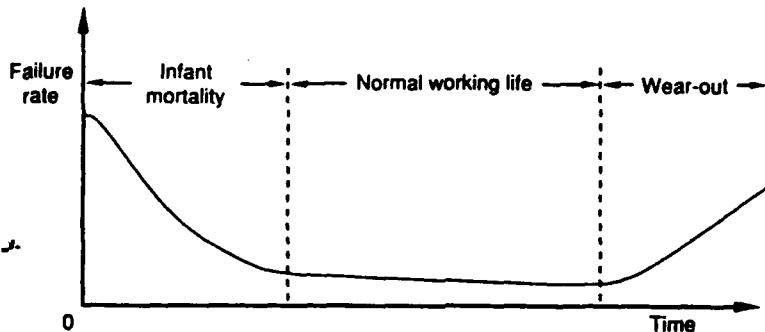


Figure 5. "Bathtub Curve" [Ref. 12]

their physical structure or housing wears out first and the system is discarded. For example, how many people own PCs or VCRs which are more than ten years old? The PANSAT computer system only has to last for up to two years.

There are several factors which can influence the baseline failure rate of components in a real system during its working life. Some of them include temperature, humidity, shock, vibration, radiation, and power cycling. For terrestrial components, temperature is usually the most significant of these factors. The failure rate approximately doubles for every 10°C rise in temperature. This is good news for the PANSAT computer, since it will be operating in

the cold environment of space. However, this advantage must be balanced with the lack of convection cooling to get rid of internally generated heat due to the lack of air.

With known component failure rates from the manufacturer, one can calculate the overall system rate by simply adding the individual component failure rates. This assumes all components are necessary for the system to work, the failure rates are independent of each other, and the failure rate of the component interconnections is minimal.

Specific failure rates are not readily available for specific components. However, failure rates of certain batches or runs of a particular manufacturing process are available for some of the radiation hardened parts [Ref. 13:pp. 14-16--14-20]. For other non-radiation hardened parts, such as the serial communications controller (SCC) or the SRAMs, one can make a rough estimate using Wakerly's text [Ref. 12:p. 674]. The EPROMs, SCC, and SRAMs will be treated as LSI parts. A FIT of 250 will be used for them. For the remaining chips, a FIT of 50 should be conservative enough. Finally, a FIT of 15 will be used for the 50 or so resistors, capacitors, and the crystal. One can calculate the tentative failure rate for the prototype PANSAT computer system, λ_{sys} , as follows:

$$\lambda_{sys} = (9 \times 250) + (15 \times 50) + (50 \times 15) = 3750 \text{ failures/10}^9 \text{ hours.} \quad (4)$$

The mean time between failures is $1/\lambda_{sys}$, or about 30 years.

5. Radiation Hardening

Another advantage of using an 80C86 based system, alluded to above, is that almost all the required parts are available in a radiation hardened version. This greatly increases the system reliability (as well as the expense). The low earth orbit that PANSAT will occupy does not strictly require the use of radiation hardened components [Ref. 14:pp. 34,80]. However, reliability vis-à-vis solar and extrasolar radiation (and manmade nuclear EMP) is enhanced by the use of radiation hardened parts. If money is no object they can be used with this design.

6. Environment

Consideration of the space environment impacted the design primarily in the selection of components which were available in a radiation hardened version.

a. Launch

Launching parameters had no direct influence on the design.

b. Orbit

The orbit has not been determined. But the use of radiation hardened parts will almost certainly gain a reliability advantage regardless of the final orbital

parameters. This again argued for the use of the 80C86 or any other processor available in a radiation hardened version. The orbit also has a direct effect on the frequency and limits of temperature extremes. Because PANSAT is small and inexpensive, the only thermal stabilization will come from the satellite structure design and subsystems placement, and possibly reflective or absorptive coatings. The processor and support chips are available which will operate reliably in the range of approximately -55°C to $+125^{\circ}\text{C}$.

7. Power

Available power on a satellite is limited. Static power consumption was a consideration in choosing the 8086, because it is available in a CMOS version, the 80C86. CMOS consumes much less quiescent power, although dynamic power consumption is a linear function of operating frequency.

8. Communications Protocol

The tentative communications protocol to be used is the AX.25 amateur packet-radio link-layer protocol. This protocol follows, in principle, the CCITT X.25 protocol, with the exception of an extended address field and the addition of an Unnumbered Information (UI) frame. It was designed to be a mechanism for the reliable transport of data between two signaling terminals, in this case between a satellite and a ground station. [Ref. 15:p. 1]

a. Error Detection

Both the sender and receiver calculate a frame-

check sequence to make sure a frame was not corrupted by the medium. In addition, there are several link-layer errors which are recoverable without terminating the connection due to things like the I frame information field being too long, or the reception of a frame with an invalid Send Sequence Number (N(S)).

b. Error Correction

The protocol handles communications errors by retransmission. Errors due to transients in the medium or the hardware can be fixed this way. A permanent hardware fault in a ground station, once detected by the protocol, can be fixed. There are limited options for error correction if a hardware fault occurs on the satellite. Hardware redundancy with automatic switching upon error detection, or switching commanded from the ground are options, but to keep the design simple hardware redundancy and error correction have been forgone. The emphasis has been placed on hardware reliability, negating the requirement for (hardware) error correction.

E. PREVIOUS FLIGHT DESIGNS

At least three other satellites have been launched with successful missions similar enough to that of PANSAT to provide useful information and insights. Taken together, they show that amateur packet radio store-and-forward message

service with the AX.25 communications protocol is feasible. It can be done because it has been done before.

1. UoSAT-2

The UoSAT-2 was designed to investigate the technical feasibility of store-and-forward communications via inexpensive satellites. It was launched in 1985 into an 800 kilometer polar orbit and it was designed to operate for more than three years. It utilized a NSC-800 processor running at 0.9 MHz. The communications link operated at 1200 bps, using a custom message protocol (MSG2). The kernel implementing the protocol was written in Z-80 assembler code and occupied 2.5 kilobytes of error detection and correction protected (EDAC) 12 bit wide RAM. This satellite was the first civilian demonstration of an operational store-and-forward communication system. Its on-board EDAC hardware provided invaluable data on the frequency of hard and soft radiation induced errors. It found that about 6 single-event upsets (SEUs) per day would occur in a 1 megabyte commercial grade CMOS memory in that orbit. Of course, the SEU rate depends on: [Ref. 16]

- Memory device manufacturing technique (radiation hardening)
- Device geometry
- Shielding
- Satellite orbit
- Satellite attitude
- Solar activity
- Geomagnetic activity

2. UoSAT-D

The UoSAT-D was a packet communications experiment that built on UoSAT-2. It implemented the AX.25 packet radio protocol operating at 9600 bps in full duplex mode. It utilized an 80C186 processor running at 8 MHz. Its mission was to support amateur packet-radio communications using low earth orbit satellites and to study the orbital radiation environment and its effects on semiconductors. [Ref. 17]

3. FO-12

The FO-12 was the first Japanese amateur satellite, launched in August of 1986, to serve as a store-and-forward digital mailbox. It implemented the AX.25 protocol with four uplink channels and one downlink channel, all operating at 1200 bps. No ROM was used. Only DRAM was used. Initial program load was accomplished via hard-wired logic. The FO-12 also used a NSC800 processor. [Ref. 18]

II. ORIGINAL DESIGN CHOICES/PROTOTYPE CHANGES

Changes have been made to the original design primarily for three reasons--expense, advance in the state of the art, and expediency. For the prototype, military standard or commercial grade were substituted because they are functionally equivalent and much less expensive. The wire-wrapped breadboard and flight model components may also have to be changed in response to changing mission requirements.

A. PROCESSOR SELECTED

The prototype uses an 80C86 microprocessor, commercial grade, instead of the 80C86RH radiation hardened version because they are functionally equivalent and the 80C86 is much less expensive. This expense was the main reason for chip substitution for all the other chips, with the exception of the Zilog serial communications controller (SCC). See below.

B. PROCESSOR MODE

The prototype stayed with minimum mode instead of maximum mode because this is still a small stand alone system.

C. BUS DEMULTIPLEXING

The wire-wrapped prototype still used the 54HC573 octal D-type address latches and the 54HC245 octal tri-state data

bus transceivers because there was no need to change them. They are available in radiation hardened versions and are fast enough to operate at 5 MHz.

D. CLOCK AND PERIPHERALS

1. Analog to Digital Converter

The A/D converter is not implemented, but it would be straightforward to implement once the telemetry/sensor requirements are determined.

2. Parallel Port

For the same reason, the parallel port is not implemented.

3. HDLC

The CMOS 85C30 was substituted for the "TTL only" 8273 HDLC because the anticipated orbit was changed to a lower one and radiation hardening was determined to be not as critical. The 8273 was not available in a CMOS version at the time of the original design. The TTL 8273's radiation immunity was traded for the reduction in power consumption by using the CMOS 85C30 serial communications controller.

4. Timer

The 82C54 programmable interval timer is still used. Its primary function is to serve as the transmitter control watchdog timer. For some of the testing, a functionally equivalent subset, the 82C53, was substituted.

5. Interrupt Controller

The 82C59 programmable interrupt controller is still used.

6. I/O Device Chip Selection

The 54HC138 3-line to 8-line decoder/multiplexer is still used. However, the address selectors were changed to A7 through A10, instead of A3 through A5, for added flexibility [Ref. 19].

7. Clock

The 82C85 static clock controller/generator and the 74C161 synchronous binary counter are still used.

8. I/O Device Timing

There has been no significant change.

9. Reset

The 82C54 still acts as the watchdog countdown timer. If the processor is operating properly, the watchdog timer will be reset before it has a chance to time out and reset the processor. However, in the original design, if the timer timed out, a flip-flop would switch to an identical ROM and the system would reinitialize. This would provide for the correction of a hard fault in the first ROM. In the interest of expediency, the actual flip-flop and extra ROM was not built. It would be easy enough to include it in the flight model, however.

10. Miscellaneous changes

A reset switch has been added to the prototype for an

on-board reset capability and an LM7805C 5 volt voltage regulator chip have been added to the board between the external power and the rest of the board. Also, an MC1488 line driver chip and an MC1489A line receiver chip have been added to the board for conversion of the RS-232C voltages of +4 volts and -3 volts to the CMOS logic voltages of 0 and +5 volts, respectively. The RS-232C connection should be used to download program code or test messages during the next phase of the board's testing.

E. MEMORY SYSTEM

1. (E)PROM

The original design used two 2k x 8 bit PROMs in tandem. The breadboard prototype uses two 128k x 8 bit TMS27C010 PROMs in tandem. This is certainly more than is required for the on-board operating system, or at least the boot-strap kernel, but it made the construction symmetrical and gives plenty of room for experimentation.

2. Vital RAM

The wire-wrapped prototype doesn't have a vital memory section. The actual size of protected memory required can not be determined without a firmer idea of how much telemetry or other vital data will be required. One could go back to using the current 128k x 8 PROM memory space and splitting it into a much smaller actual PROM portion with the balance of the 128 k x 8 space being taken up with radiation

hardened/shielded redundant SRAM. Perhaps this address space could be occupied by special 12 bit EDAC memory as in the UoSAT-2.

3. Bulk RAM

The original design used 32k x 8 bit SRAM chips with extra 54HC138 multiplexers and 54HC32 OR gates for addressing. Due to rapid advances in the state-of-the-art, 128k x 8 bit memory chips were available for the wire-wrapped prototype, dividing the RAM memory chip count by four and eliminating the need for five 138 decoders and eight 32 hex OR gate chips.

F. LOGIC DEVICE FAMILY SELECTION

1. CMOS v. TTL

The original design was done with CMOS instead of TTL because, as can be seen in Figure 6 on the next page [Ref. 20:p. 569], all the CMOS logic families use less power than their TTL counterparts and most CMOS families are fast enough to operate at 5 MHz (With the exception of the C family.)

In addition to reliability, low power consumption is a primary goal in the design of satellite circuits. The following three differences dictated the use of CMOS versus TTL components in the design. Factors which determined the particular family of CMOS selected are also discussed.

a. Speed

As stated, for the breadboard prototype, CMOS was

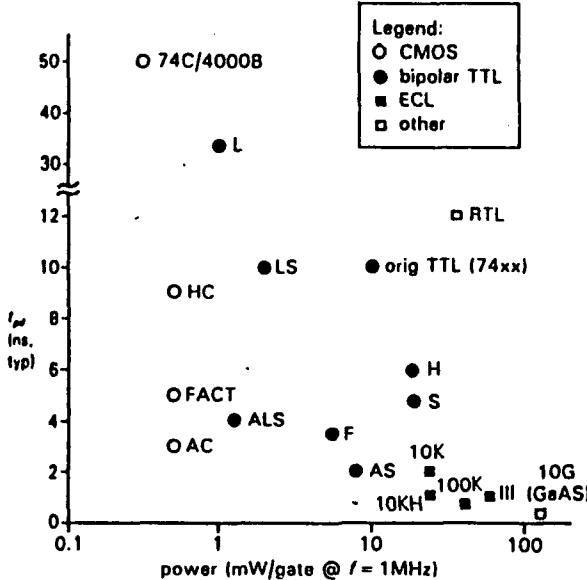


Figure 9.2. Speed versus power for various logic families.

Figure 6. CMOS v. TTL Relative Power Consumption & Speed [Ref. 20]

used because at 5 MHz CMOS dissipates less power than TTL although many TTL families are as fast or faster. But this is not a high speed design. The CMOS HC family was specifically selected for the design, instead of the C family because "...The speed range of CMOS goes from about 2 MHz (4000B/74C at 5V) to about 100MHz (for AC/ACT)." [Ref. 20:p. 486] Because the processor is only being driven at 5 MHz, or less, speed considerations argue for the use of CMOS HC family parts or faster. The 82CXX family of parts, used because of the ease of conversion to a nearly totally radiation hardened circuit, all operate to at least 5 MHz or better.

b. Power

One disadvantage of CMOS is that, as the operating frequency increases, so does the power dissipation. Even so, the total power dissipated at 5 MHz will still be well below that of TTL. [Ref. 20:p. 487] Figure 7 shows this clearly.

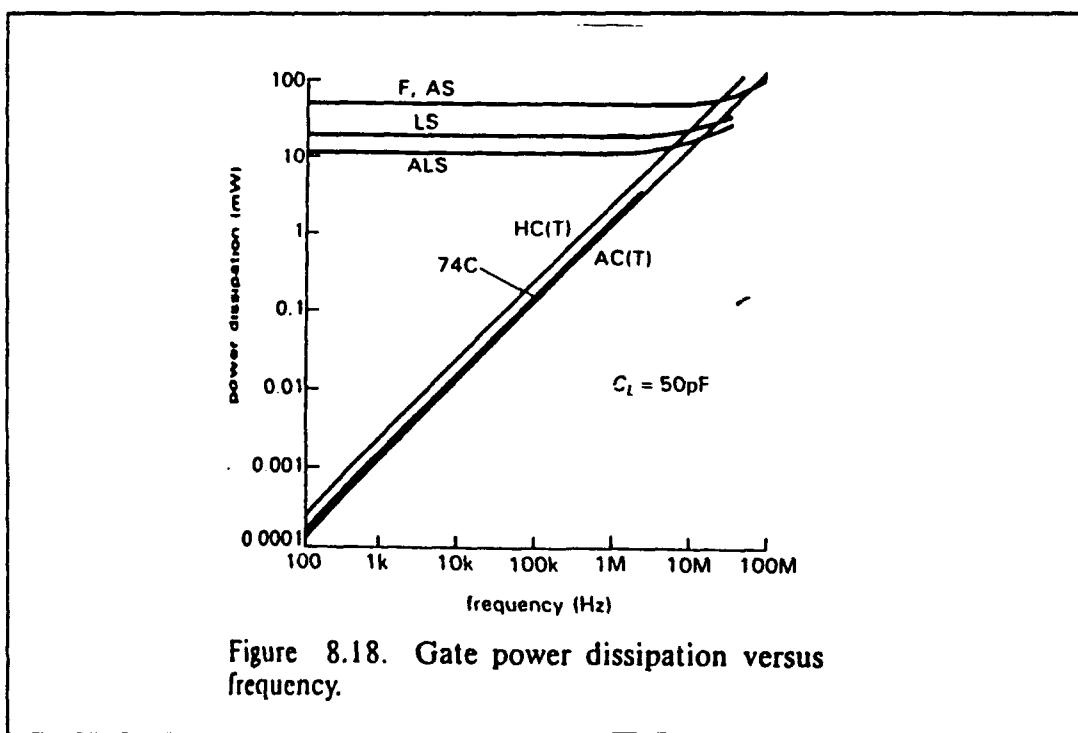


Figure 8.18. Gate power dissipation versus frequency.

Figure 7. CMOS Power Dissipation v. Frequency [Ref. 20]

c. Noise immunity

CMOS has slightly better noise immunity than TTL, for most circuit configurations. HC and AC family CMOS have the best noise immunity of all the CMOS families. [Ref. 20:p. 569]

2. Compatibility

Any CMOS family, operating at 5 volts, is compatible with any other CMOS family [Ref. 20:p. 569]. It is probably best to have all the parts of a circuit be of the same family, which is the HC family in this case.

3. MIL-SPECS

Finally, for the parts other than 82CXX, the 54HCXX versions should be used for the final flight version of the circuit. The 54 prefix means that the component meets more rigorous temperature and reliability standards than the commercial grade series, 74. For example, a 54 series component will be able to operate in a temperature range of -55°C to $+125^{\circ}\text{C}$, and can withstand + or - 10% power supply variations whereas a 74 series component can only operate from 0°C to 70°C and can only withstand + or - 5% power supply variations [Ref. 21:pp. 244,247]. That extra temperature margin, especially, could be important in the harsh environment of space. (Some schematic components are designated as 74 series.)

III. WIRE-WRAP CONSTRUCTION AND TESTING

A. BOARD LAYOUT

The layout of the board with its components is shown in Figure 8 on the next page. One can see that the chips are as close together as possible, consistent with having enough room to install filter caps and/or current limiting or pull up resistors if or when needed. An attempt was also made to arrange the components so as to minimize wire lengths while taking into account the required circuit interconnections.

1. Wire Size(s)

The wire size used was AWG 30. One of the references, however [Ref. 21:p. 119], recommended that AWG 20 be used for all IC power and ground lines. Unfortunately, the wire wrap tool is designed for AWG 30. One solution would be to make double runs of the AWG 30 wire to simulate AWG 20. However, all the chips drew so little current that voltage drop was not a problem. The wall power supply current meter never read more than about 80 milliamps.

2. Heat Dissipation

With CMOS, heat dissipation is not really much of a concern. On the prototype board the chips have stayed cool to the touch, even during extended periods of testing.

3. Component Placement to Minimize Wire Length

The components were not just arbitrarily placed on

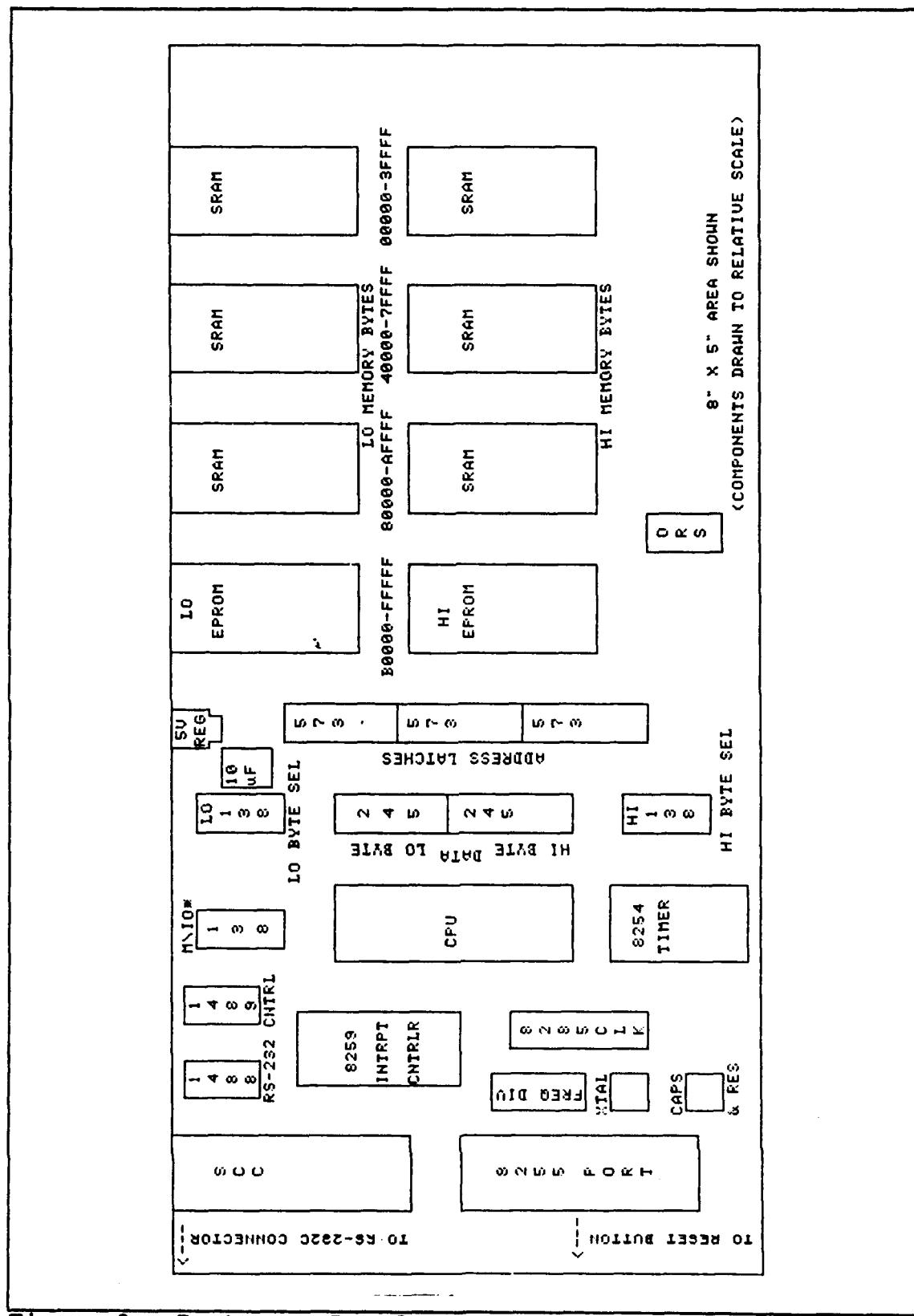


Figure 8. Prototype Board Layout

the wire-wrapped board. The components were placed so as to minimize wire lengths. Some of the reasons for minimizing wire lengths are described below.

a. Stray capacitance

Stray capacitance's effect on a digital circuit is to act as an AC load. An AC load is undesirable because it can slow down transition times. There are at least three things which can cause stray capacitance in a digital circuit:

- Output circuits--typically several pF
- Input circuits--typically from 2 to 15 pF
- The wiring that connects outputs to other inputs--typically 1 pF per inch, or more.
[Ref. 12:p. 74]

The first and second items are inherent to the I.C. packages themselves. The only factor which the wire-wrap circuit builder has control over is the length of the wiring. Fortunately, the circuit is only being driven at 5 MHz, but even so, a conscious effort was made to minimize wire length. Rise-times on any of the tested signals were not observed to be a problem. There were, however, significant voltage spikes on many rising and falling signal edges.

b. Signal Degradation and Power Drop

Standard wire-wrap size wire, 30 AWG, was used. This seemed to be at odds with the reference [Ref. 21:p. 119] which recommended at least 20 AWG or larger for all logic IC power and return lines. (Although this reference is

presumably more concerned with higher speed circuits.) Wires with a smaller cross-section are more prone to noise pickup and power drop per unit length. However, because CMOS was used with a low current draw and the computer could fit all on one board in a 5" by 8" area, the 30 AWG wire seemed to work. Double wire runs were started on some of the power and ground lines, to increase the effective AWG, but the effort was abandoned when initial testing seemed to indicate that noise and voltage drop were not a problem.

c. Propagation Delay

Another reason one should try to keep the wires as short as possible is to minimize the effects of propagation delay. Too much propagation delay could have a deleterious effect on the circuit. Such things as clock skew or missed "gates" or "windows" could cause circuit malfunction if one or more lines are particularly long compared to others. [Ref. 22:p. 119]

4. Filter Capacitors

In accordance with the *Logic Designer's Manual* [Ref. 22:pp. 117-118], a 10 microfarad capacitor was placed in parallel with a 0.01 microfarad capacitor across the incoming 5 volts from the wall power supply. A filter capacitor is used to help reduce noise. This is recommended whenever power supply lines run an "appreciable" distance to a board. However, an LM7805 5 Volt voltage regulator was later added to the board negating the requirement. Strictly speaking,

these capacitors are only recommended for circuits operating above 10 MHz anyway. However, with the fast switching times of the HC chips, harmonics may be generated which may be partially shunted by these two capacitors. It shouldn't hurt to leave them on the board. Additionally, a 0.1 microfarad bypass capacitor was placed across the power and ground connection of each chip. The reference recommends a value of 1 to 10 microfarads, but the experienced Space Systems electronics technician [Ref. 23] recommended the 0.1 microfarad capacitors be used instead.

B. CMOS POTENTIAL PROBLEMS/CONSIDERATIONS

1. Unused Inputs

One slight disadvantage of CMOS versus TTL is the requirement to tie all unused CMOS inputs high or low, as appropriate, even for unused gate sections in the same package. With TTL, one can ignore unused sections of a single chip, as well as unused input lines within a particular circuit on a chip. This is not true with CMOS. If one leaves any input line unconnected, the input level could float up to the logic threshold. This could result in both MOS output transistors conducting, resulting in excessive current draw. [Ref. 20:p. 580]

Refer to Figure 9 [Ref. 20:p. 485] on the next page, which is a standard CMOS AND gate. Suppose, for example, inputs A and B were unused but not tied off. One can see

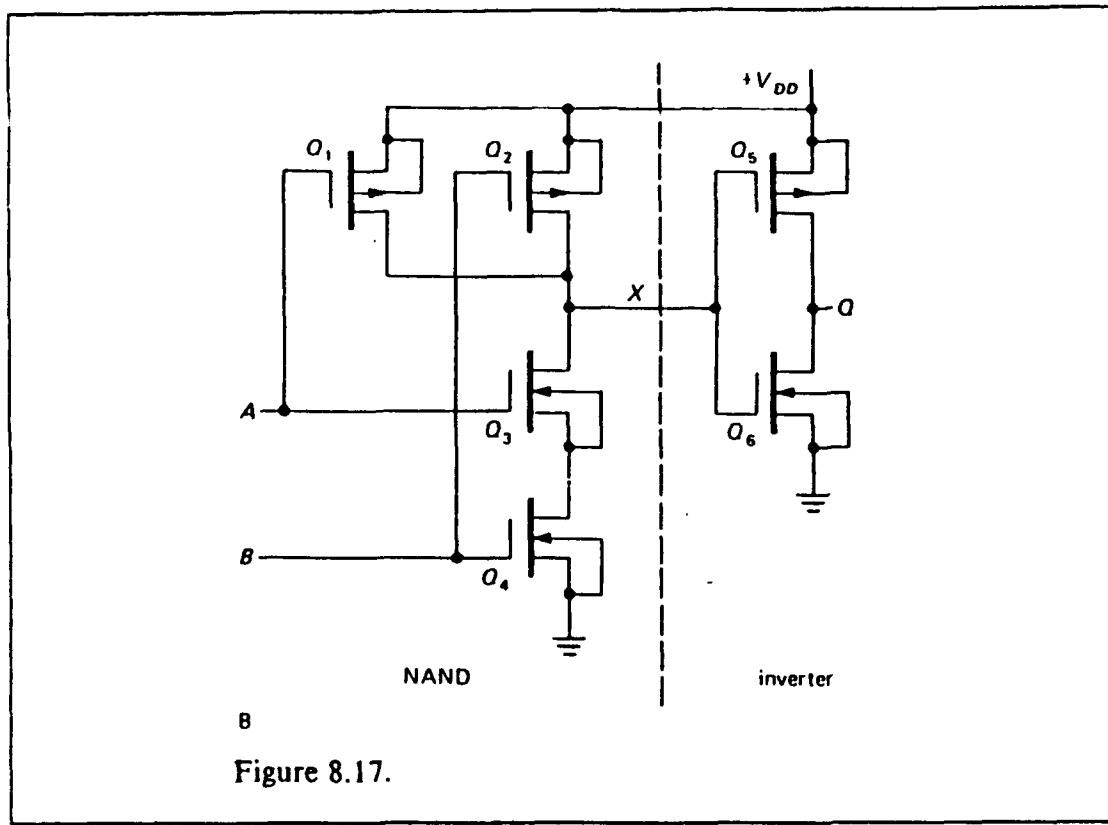


Figure 9. CMOS AND Gate [Ref. 20]

that if both of these inputs floated high enough to bias Q3 and Q4 on, but not high enough to bias Q1 and Q2 off, the resulting current flow through the low resistance path from +Vdd to ground could be excessive. This could cause latch-up (described below) resulting in temporary or permanent damage to the part.

2. Latch-up

"All CMOS devices are intrinsically susceptible to latch-up, which occurs when internal parasitic silicon-controlled rectifiers (SCRs), structures that are inherent in CMOS integrated circuits, are triggered on." [Ref. 21:p.57] The three small figures directly below (Figure 10) help to

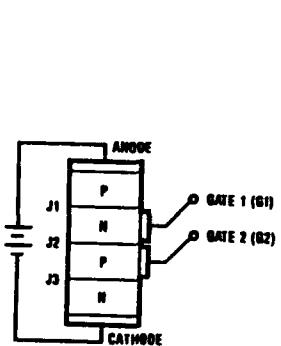


FIGURE 2. Simplified SCR Structure

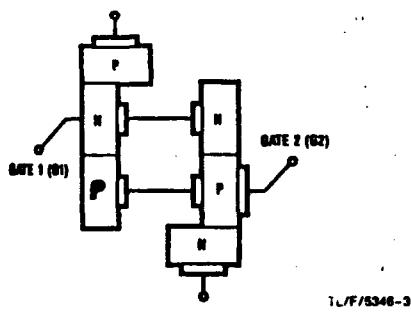


FIGURE 3. Cross-Coupled Transistor Model of SCR

Figure 10. CMOS Latch-up Process [Ref. 24]

explain the inherent problem of CMOS latch-up.

The small figures show the simplified SCR structure inherent in all CMOS devices, the effective cross-coupled transistor operation of the junctions during latch-up, and a simple circuit model of the two "transistors" involved. Normally, gate 1 and gate 2 will be at the same potential. But suppose a large positive voltage is placed across the anode and the cathode of the SCR structure on Q1. The process of latch-up can be described as follows: If enough leakage current can flow from Q1's anode to its cathode, thereby biasing Q2 on, then more current will be on gate 1, biasing Q1 on even more. This is a runaway situation which rapidly leads to saturation. [Ref. 24:pp. 2-112--2-113]

However, latch-up should not be a problem anymore with the current production methods used to manufacture the

54HCxxxx parts [Ref. 24:p. 2-112]. The latch-up problem has been eliminated with the Harris radiation hardened parts as well [Ref. 25:p. 2-11]. These are the most likely components to be used in the final design.

3. Pull up Resistors

Pull ups (or pull downs) are only required if one is driving a CMOS input with a device that has an open state [Ref. 20:p. 579]. Pull downs can be used for CMOS but they are not effective for TTL. For CMOS, noise immunity is the same with either pull ups or pull downs and there is no current draw through the resistor for either choice when the driving device is open.

There is no need for pull ups in this design. The only three state devices used in this design are the 573 octal latches and the 245 octal transceivers. The 573s are permanently enabled and any device driven by the 245s has a *chip select* signal. For example, in between *data enable* assertions, the outputs of the 245s are in a high impedance state. This is not a problem because none of the devices driven by this input, e.g., the interrupt controller or the SRAMs, will be chip selected at this time. Therefore, one will not load the devices with unpredictable data and no pull ups are required.

4. Fan out

Because all the components are CMOS (with the exception of the RS-232 drivers, to be used for testing,

which are NMOS), fan out should not be a problem with the design, with the possible exception of the *read* signal. The *read* signal is the worst case. Any of the outputs should be able to easily drive at least 10 other inputs [Ref. 20:p. 487]. The *read* signal goes to the eight memory chips, the timer, the interrupt controller, and the SCC, for a total fan out of 11. This should still be acceptable.

5. Fast Rise-times and Harmonics

These are a concern with the newer CMOS logic families [Ref. 21:p. 5] such as HC used in this design. The fast rise-times have two major deleterious effects: Faster rise-times generate higher harmonic frequencies, and faster rise-times result in greater transient voltage swings.

The bandwidth of the interconnection network on a wire-wrap board will limit the amplitude of the higher frequency components and the inductance will result in transient voltage spikes. This was observed on the signal traces in the lab and already mentioned above. The data bus signals, especially, which are interconnected with many more wires than most other signals, clearly showed variations in voltage levels. Also, voltage spikes of about 0.75 volts (or more) were observed on the system clock, for example. These problems were minimized by paying attention to the component layout, where the shorter all the interconnecting wires were, the better, as recommended in the reference [Ref. 21:p. 84].

C. INCREMENTAL TESTING

1. Clock and Clock Frequency Divider

First all unused inputs to the 82C85 and the 54HC161 were checked to make sure that they were tied either high or low. Then they were plugged into their respective chip holders and power was applied to the board. The 82C85 was putting out a 5MHz, zero to five volts clock on pin 2. The 161 was putting out a 0.3125 MHz clock (5MHz divided by 16) on pin 11. The clocks had noise of approximately 0.75 volts peak-to-peak centered around either the zero or five volt reference level. See Figure 11 on the next page.

2. CPU, EPROM, Latches, and Data Transceivers

After verifying that the 82C85 was putting out an acceptable clock, the next step was to verify that the CPU and EPROM, with their integral latches and data transceivers, were at least nominally functioning. This was done by hand coding the simplest program possible (five bytes) and burning it into the EPROMs. (Appendix A has the 8086 machine language code and the program code is in Appendix B.) The EPROMs come from the manufacturer initially "programmed" with 128K bytes of "1"s, or "FF"s. (Programming or burning the EPROM changes appropriate bits to "0"s.) The program is simply one statement--an unconditional jump to itself.

A 100 MHz oscilloscope was used to verify that the EPROM *chip select* signal (*CS**) was being asserted at the same time as the CPU *read* signal (*RD**) on pins 22 and 24,

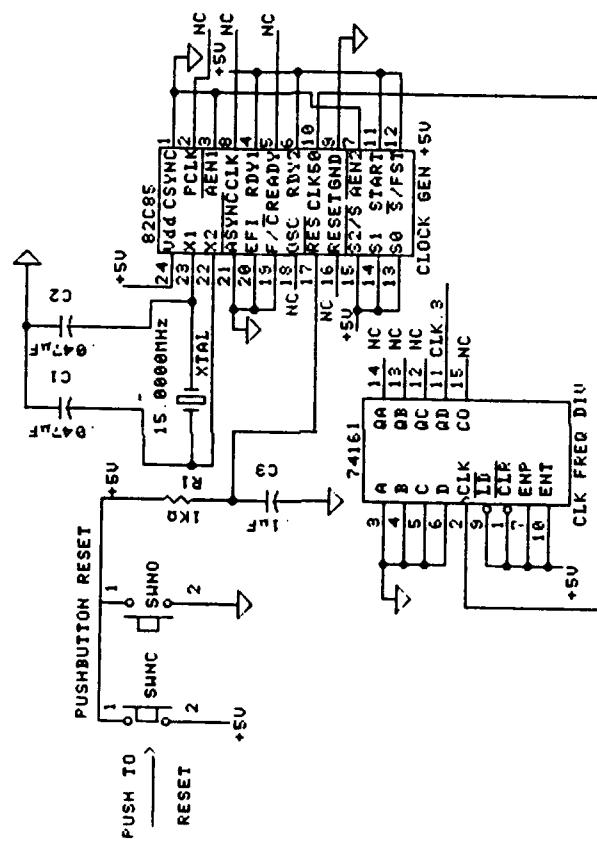


Figure 11. Clock Circuit Schematic

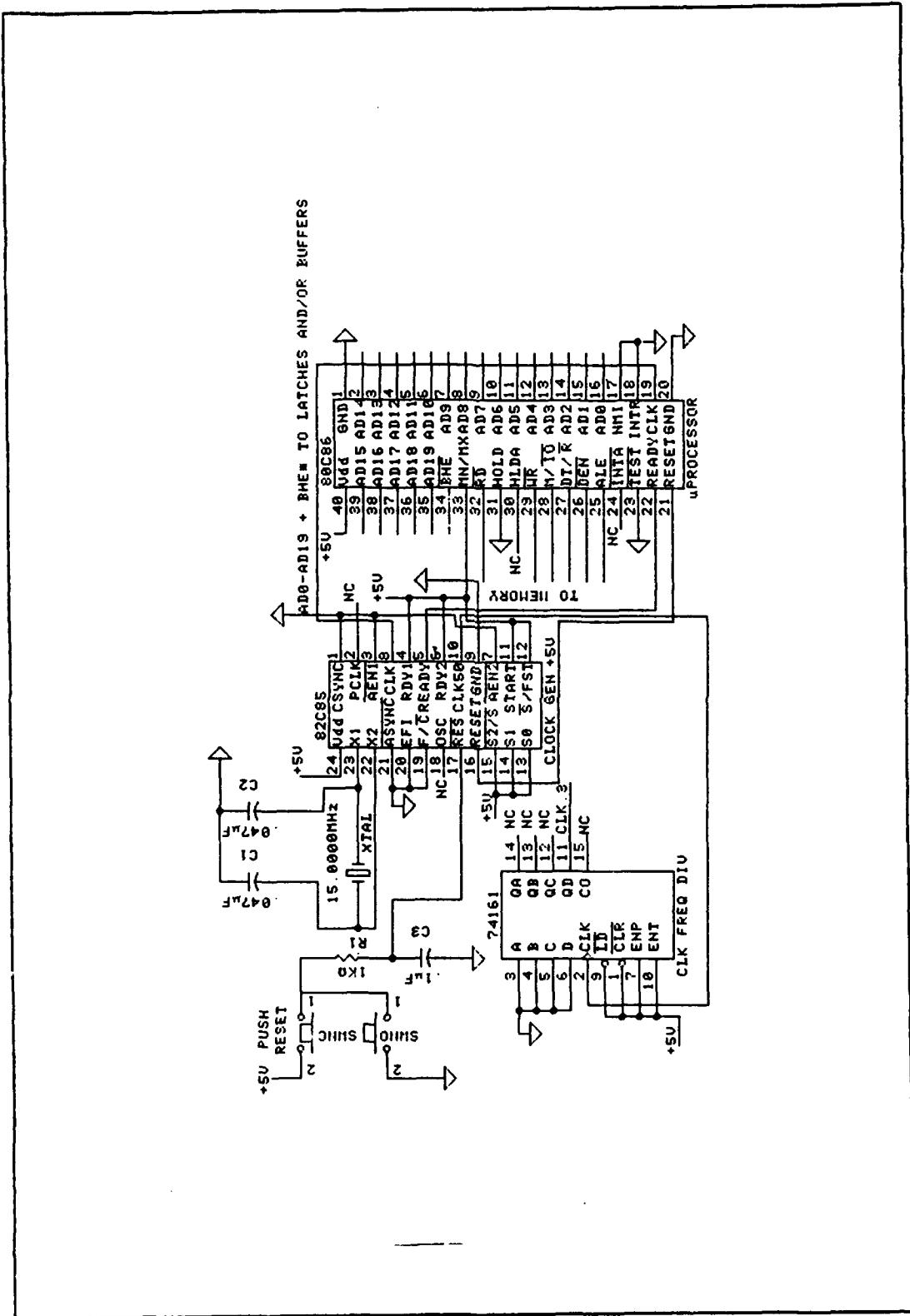
respectively, of the EPROM. Also, the address and data lines on the 573 address latches and the 245 data transceivers were checked to verify that all but A3 through A1 stayed high and that the 15 data bits changed appropriately to reflect the data transfer of "00EA", "FF00", and "(FF)FF". The relevant parts of the board for this CPU loop test are shown on the next two pages in Figures 12 and 13.

3. Memory

Next, to do an initial verification test of SRAM, a 25 byte hand coded machine language program was burned into the EPROMs for testing. (See Appendix C.) The program would jump to the start of a routine. The routine would set up the data segment register for a segment located in memory. Then a memory location (byte) would be loaded with the arbitrary number "05". Then there is a NOP (no operation) in the code. Then the same memory location is read and the value there (should be "05") is loaded into the DL register. Finally, the routine jumps to the initial jump command and the program repeats.

As above, an oscilloscope was used to verify that the address and data lines were what was expected, as well as verifying that the 2 chip select signal assertions and the read and write signal assertions happened at the right times with respect to each other. They did.

Figure 14 follows Figures 12 and 13. It shows the complete memory schematic used for this and subsequent tests.



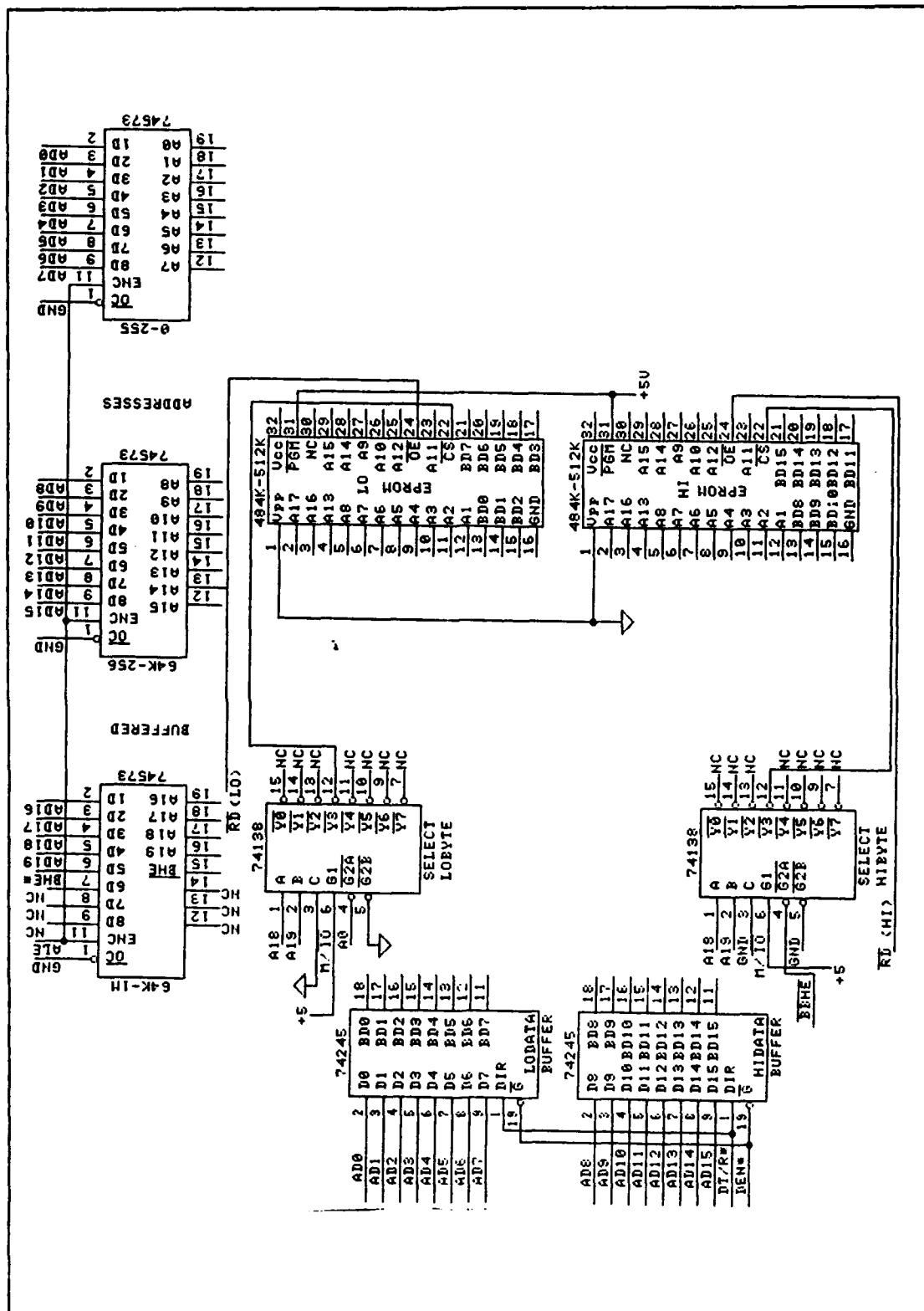


Figure 13. Loop Test Schematic--EPROM Only

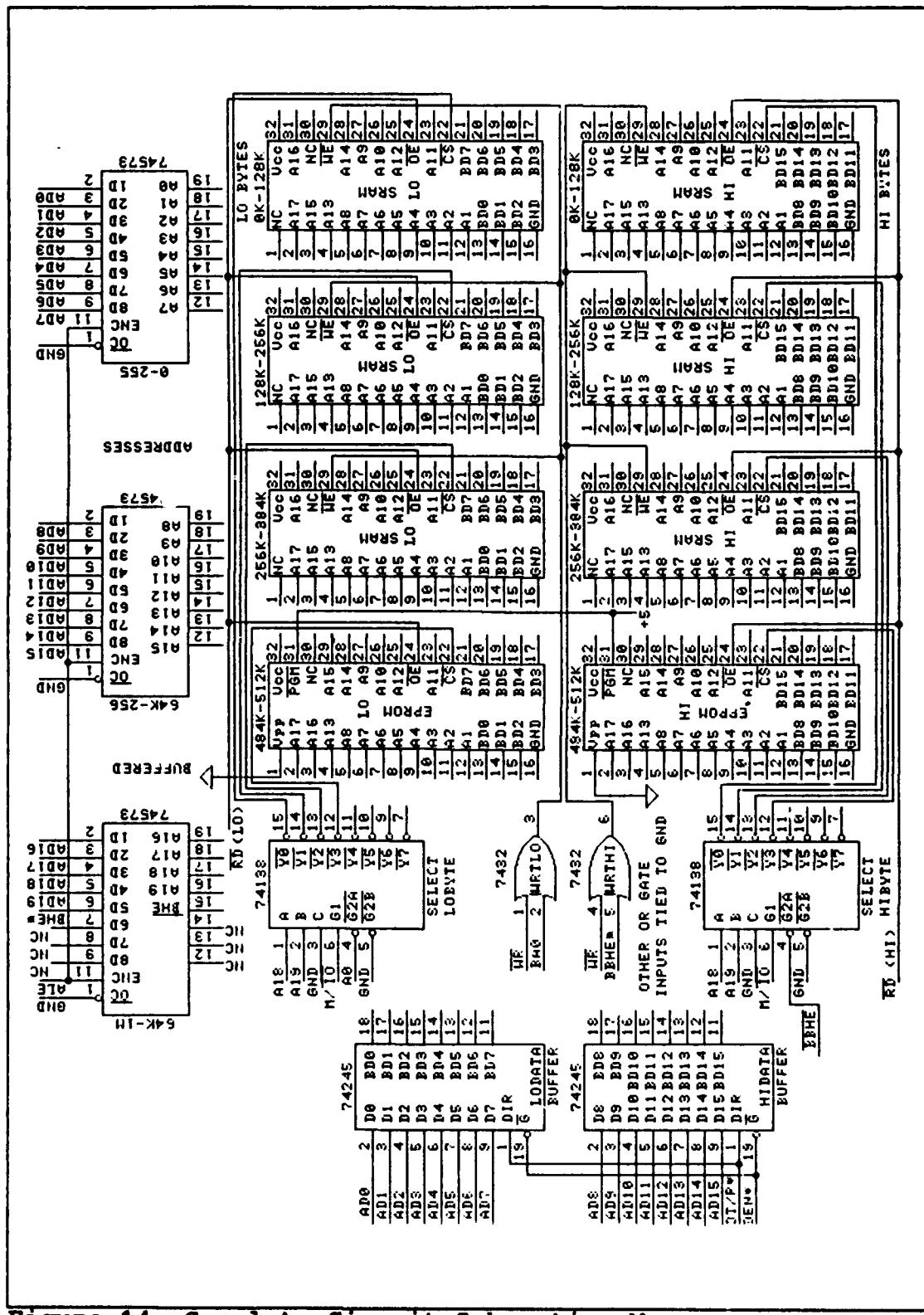


Figure 14. Complete Circuit Schematic--Memory

4. The Need for a Monitor

But now there were 15 reads and 1 write per program "cycle." It was becoming difficult to unambiguously verify correct circuit operation. It was becoming evident that a better way to monitor circuit operation than sticking an oscilloscope probe on various chip pins would need to be found. Also, the capacitance of the oscilloscope probe, itself, has the potential to change the circuit parameters (for HC CMOS, at least) just enough to make a circuit work which otherwise would not, or vice versa [Ref. 20:p. 575].

In fact, this phenomenon was observed in the lab. Often, the oscilloscope would indicate the circuit was not operating properly and would have to be reset, as one went about the circuit with the probe checking inputs or outputs on various pins. However, if the probe(s) was (were) clamped onto the circuit and a correct oscilloscope trace was obtained, the trace would remain unchanged for two hours or more. This was observed several times.

This also argues for a more reliable and less invasive means of monitoring the circuit performance. So the next goal, after completion of the complete incremental system check out, should be to set the board up with an RS-232C connector. Then the board could be hooked to a CRT monitor. The Space Systems technician had a monitor program available, written in assembly, which would allow the target board to be hooked up to a PC host. If this monitor program

and hardware were installed, then one could write assembly, or higher level compiled programs, which could then be downloaded to the target RAM. This would eliminate the requirement for the tedious bother of machine language level hand coding and burning of the EPROMS.

But the monitor program requires extensive modification for application to the board's particular components and configuration. This has been left for the student(s) who will follow on. There was not enough time to sidetrack into the extensive set up of the complete monitoring system.

5. Timer

Before testing the timer directly a short program was written to test the M/IO* selection circuitry. This was done by running a program which would run a continuous loop which would select the unused pin number 10 (Y5 on the schematic) on the 54HC138 decoder with an appropriate OUT statement. (Register DX already having been loaded and register AL being all *don't cares* in this case.) (See Appendix D.) A periodic high pulse was observed when the IO command OUT was executed and pin number 10 on the 138 IO decoder was periodically selected. Figure 15 on the next page shows the pertinent circuitry.

Now that the M/IO* selection circuitry was shown to be working, the next step was to write a simple test program for direct testing of the 82C54 programmable interface timer.

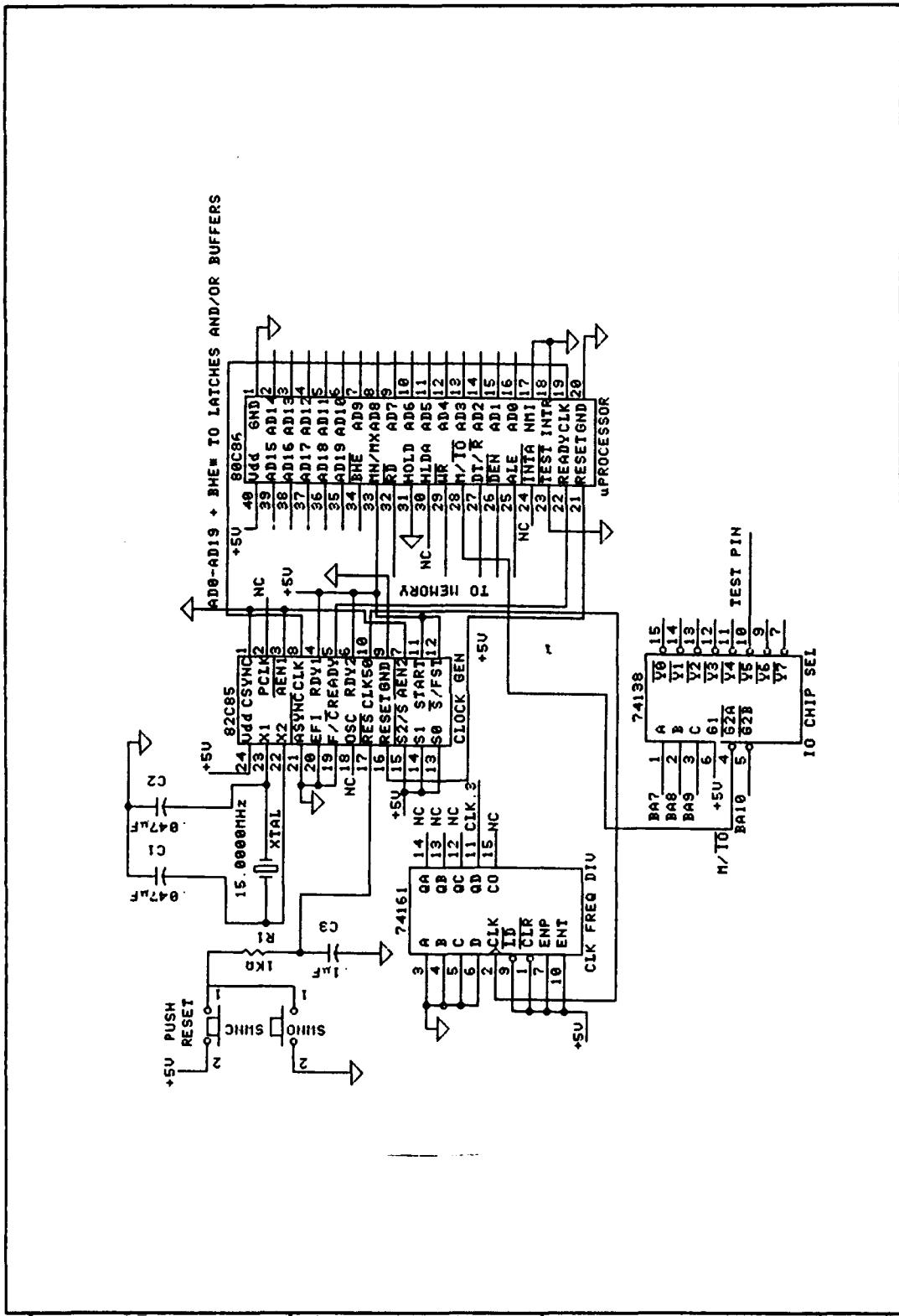


Figure 15. Memory/IO Test Schematic

Counter 2, Mode 3, was selected with an initial count of four. This should have resulted in a square wave on the OUT2 output with a period of four 82C54 clocks. That is what was observed. (See Appendix E.)

6. Interrupt controller

Originally, this was to be the final portion of the piecemeal testing of the hardware components. It was also the most difficult. Initially, a program was written to test both the 8259 and the SCC at the same time. The timer was used in Mode 0 to provide a periodic interrupt signal. (In Mode 0, the timer stays low until it times out; then it goes high.) Part of the interrupt service routine (ISR) was to reset the timer as well as read a previously stored character from memory and write it to the SCC which would put the character out at 9600 baud.

But this turned out to be too ambitious for one program (i.e., it would not work), so the program was split into parts. Thus, the SCC was left out of its holder and the program would just put out the stored character to the SCC port address. It was hoped that the data's periodic presence on the SCC chip holder data pins would be observable. This would verify proper operation of everything except the SCC itself.

The SCC could be tested separately, without using the timer or the interrupt controller, by having the CPU poll the SCC until its transmit buffer was empty and it would then be

ready to accept another character from the CPU. Then, after all the components were verified as functioning correctly, they could all be tested as a complete system much more effectively after implementing the suggested monitor program with the RS-232C protocol.

This test of just the timer and the interrupt controller could not be made to work, either. It appeared as though the timer was not being reset, because *OUT2* stayed high and the CPU was cycling through low memory. Evidently, the CPU was putting the return address on the stack and then it was being immediately interrupted again, whereupon it again put the return address on the stack, and so on. The act of cycling through low memory indicated that the stack segment and the stack pointer had not been initialized.

But even so, the program still should have worked. The return address would just be located at 00000, 0FFFF, 0FFE, and 0FFFD.

So the interrupt controller testing program was again broken into smaller parts with the first part being a test of the timer, alone, in Mode 0. (See Appendix F.) This first incremental program was finally made to work, but only after discovering that the 8254 data sheet's functional description was wrong.

But first, it was thought that it might be a problem with the timer taking too long to go low after being reset. Since the 8259 is clocked 8 times faster than the timer and

the CPU is clocked 16 times faster than the timer, perhaps the 8259 reset was happening too quickly upon the heels of the timer reset? This is why there are delay loops between the timer reset and the 8259 reset. After the real problem was discovered, it was realized the delay loops are almost certainly not necessary, but it doesn't hurt to have them there to remove all doubt.

The first increment of the 8259 testing program shows what was later realized to be probably the main or only reason why the original program did not work. The data sheet on the 8254 timer is wrong. The data sheet says that once the timer times out in Mode 0, one needs only to reload the control word (CW) or reload the count and the timer will resume counting. Evidently, one needs to reload both the CW and the initial count for the counter to resume counting. The timer stayed high if one reloaded the CW, only. When one ran the program which resets both the CW and the initial count, suddenly the address and data lines and the timing relationships were all as expected. Figure 16 on the next page shows the circuit for the testing of the 82C54 (or 82C53) countdown timer.

The second increment of the interrupt controller testing used the timer in Mode 0 to provide the periodic interrupt. (See Appendix G.) OUT2 is used as a signal to the 8259 on IR3 that there is an interrupt to be serviced. The 8259 alerts the CPU with the INT line. The CPU replies with

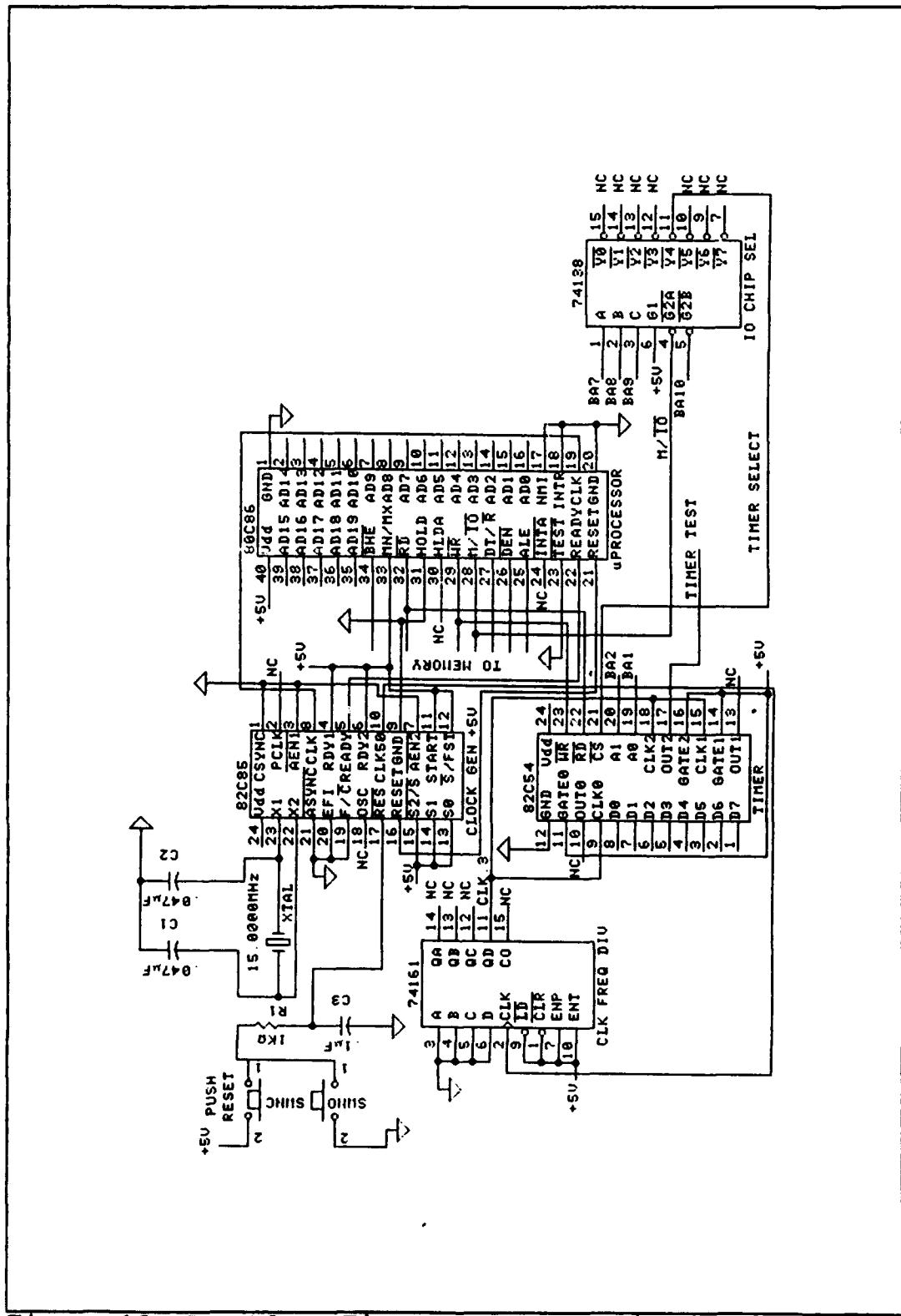


Figure 16. Countdown Timer Test Schematic

*INTA** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself must have first been loaded into memory.) The ISR just resets the timer. One must be careful not to enable interrupts until the timer actually goes low again. Otherwise, the CPU will keep interrupting itself and the ISR to reset the timer will never be executed and *OUT2* will stay high (causing interrupt upon interrupt) and the CPU will cycle through memory doing nothing but continually putting the return address on the stack, as already discussed above. (See Figure 17, next page.)

Also for the reasons already discussed above, it was very difficult to verify proper circuit operation for this increment. The only way to verify the circuit now was to trigger a trace on the oscilloscope with something like one of the ISR SRAM chip selects and check to see if the cycle time was what would be expected if the program were operating properly. Sometimes the reset button had to be pressed several times to get a steady trace with the correct cycle time. It was not clear, though, if the instability was an artifact of improper circuit operation or of a problem with the scope triggering mechanism.

Finally a steady trace was obtained from the chip select signal on the stack segment low byte SRAM (memory locations 40000 to 7FFFF). On the 0.02 msec per division scale, the cycle was 8.5 divisions long. This is 0.00017

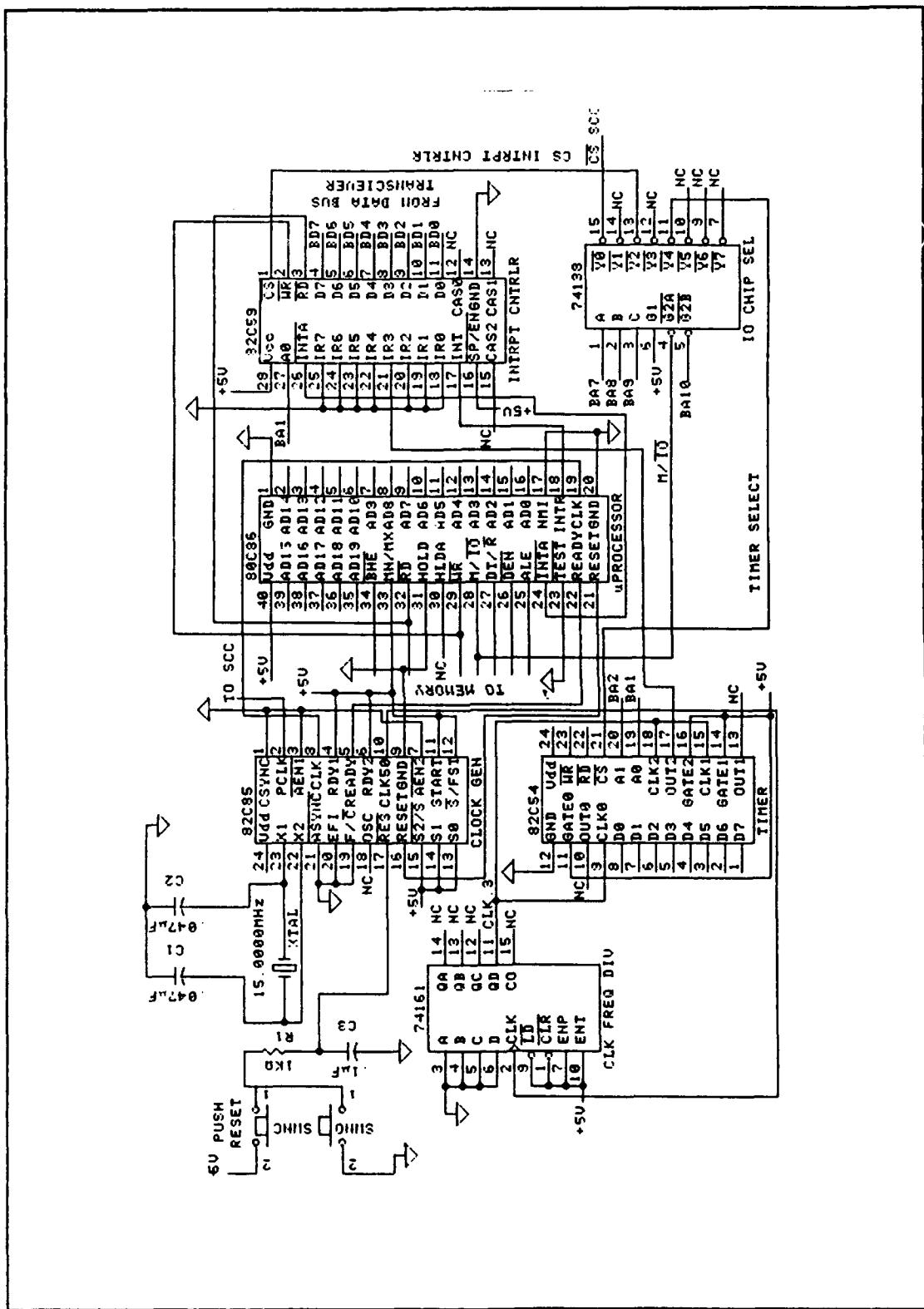


Figure 17. Interrupt Controller Test Schematic

seconds per cycle. Since the counter is loaded with 2Fh (= 47d), it should take $47d \times 1/(5 \text{ MHz}/16) = 0.0001504$ seconds to complete. But of course, there is overhead time in reinitializing the counter when it times out. The return address has to be placed on the stack and the vector address of the ISR has to be loaded. Then the DS and DI registers have to be initialized. Finally, the CW and the initial count can be written to the timer and the timer will count down for 0.001504 seconds again. This accounts for the difference of the 98 or so CPU clock cycles between 0.000154 seconds and 0.00017 seconds.

Figure 18 (Page 60) is a copy of a Polaroid picture of the oscilloscope trace of chip select on the 40000-7FFFF, low byte memory SRAM. It shows the previously mentioned edge spikes very clearly. It also shows one cycle of a repeating pattern. There are 12 chip selects per cycle. This is expected. If one looks at the ISR code in the appendix which is run from memory location 40000h to 4001Dh, one will see there are 12 separate reads of code (a word at a time) between op code executions, i.e.:

- BA 06 1
02 B0
(BA 06 02)-->LOAD DX with 0206
- B0 EE 2
(B0 B0)---->Load AL with B0
(EE)----->Write AL to counter 2
- BA 04 3
02 B8
(BA 02 04)-->LOAD DX with 0204
- 2F 00 4
(B8 2F 00)-->Load AX with 002F

•	EF B0	5
	(EF)----->Write to counter 2 with 002F	
•	08 48	6
	(B0 08)----->Load AL with 8	
	(48)----->Decrement AX	
•	3C 00	7
	(3C 00)----->Compare AL with 0	
•	EB 49	8
	(EB 49)----->Jump back 7 to code 48	
•	74 02	9
	(74 02)----->Jump to next code if AL = 0	
•	BA 00	10
	01 B0	
	(BA 00 01)--->Load DX with 0100	
•	20 EE	11
	(B0 20)----->Load AL with 20	
	(EE)----->Write AL to 8259	
•	CF FB	12
	(FB)----->Enable interrupts	
	(CF)----->Return from ISR	

These 12 separate reads correspond to the 12 chip selects shown in the figure. (Probably not in this order.) This gives an example of the kind of procedure(s) followed to verify proper circuit operation.

Finally, for the third increment, a program was again written to repetitively output a stored character directly to the SCC. (See Appendix H.) This program was tried and it could not be made to work. The circuit, or the oscilloscope triggering, was just too unstable. Perhaps the program was incorrect (not likely because only a very small new part was added), or perhaps it was a function of some kind of performance margin being exceeded with respect to the SRAM memory. This problem would take too much time to solve without more advanced monitoring tools. The implementation of the host and target monitor system already mentioned

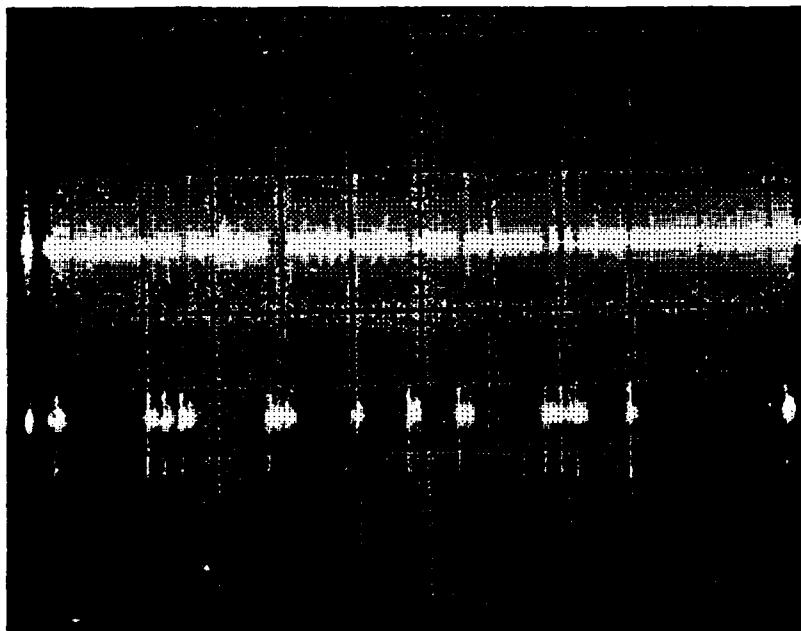


Figure 18. Interrupt Controller Test--Increment 2

should settle the issue. However, the interrupt controller was already shown to work, so a program was written to test just the SCC by itself to complete the hardware verification.

7. Serial Communications Controller (SCC)

The last program, to test the SCC, is shown in Appendix I. The CPU sends a character to the SCC's transmit buffer and the SCC is (or should be) programmed to put the character out at 9600 baud. For the first part of the program, the SCC is initialized to transmit the character at 9600 baud. Then, after the CPU reads the character from memory and loads it into the SCC's transmit buffer, the CPU keeps polling the SCC until it finds the SCC transmit buffer

empty. When the CPU finds the buffer empty, it sends the SCC the same character from memory again and the process repeats.

One should detect a single character stream from the SCC at 9600 baud. A CRT was procured to hook up to the RS-232 port so the character could possibly be seen on the CRT screen. It was not clear from the data sheets available on the 85C30 SCC in the component catalog [Ref. 26] exactly how to set all the bits in the various control registers. The program in the appendix could not be made to work. (A Zilog technical representative was contacted and he explained it was very difficult to program the SCC with only the component description in the component catalog. He said he would be mailing the proper information. [Ref. 27])

Then the error was discovered. The final "EE" in the write registers initialization sequence had been inadvertently left off, so of course the baud rate generator was not enabled. This was corrected, and then one could see the *serial data out* pin going high and low at some changing frequency. One could only get a flash of the pulse as it periodically traversed the oscilloscope screen. This inability to lock on the signal is most likely caused by the character being put out at slightly different times on each pass. The CPU is so fast in executing the Tx buffer empty check loop that an inconsistent number of loops is probably performed each time before the next character is fetched and loaded in the SCC transmit buffer. Figures 19 and 20 on the

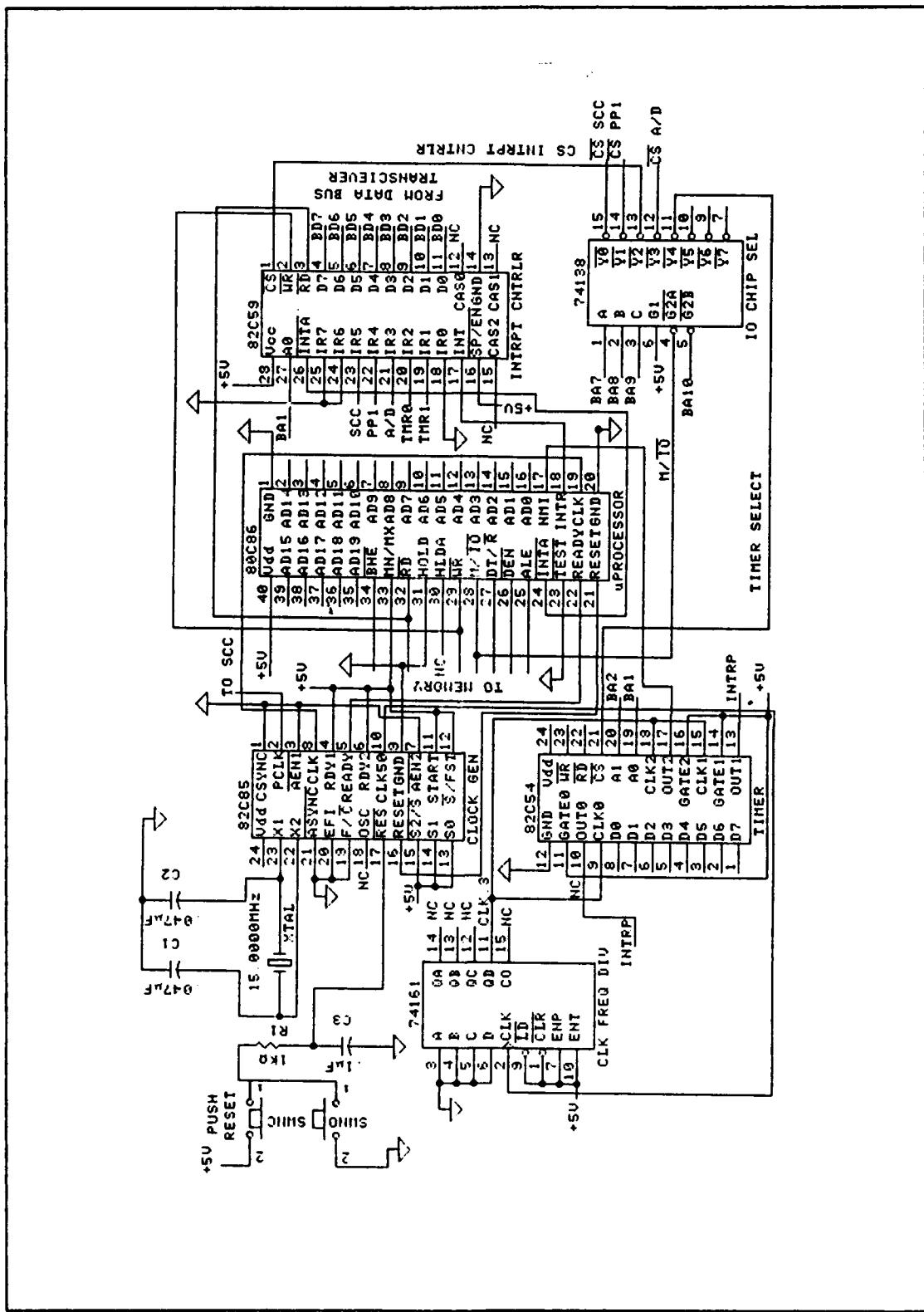


Figure 19. Complete Circuit Schematic--CPU

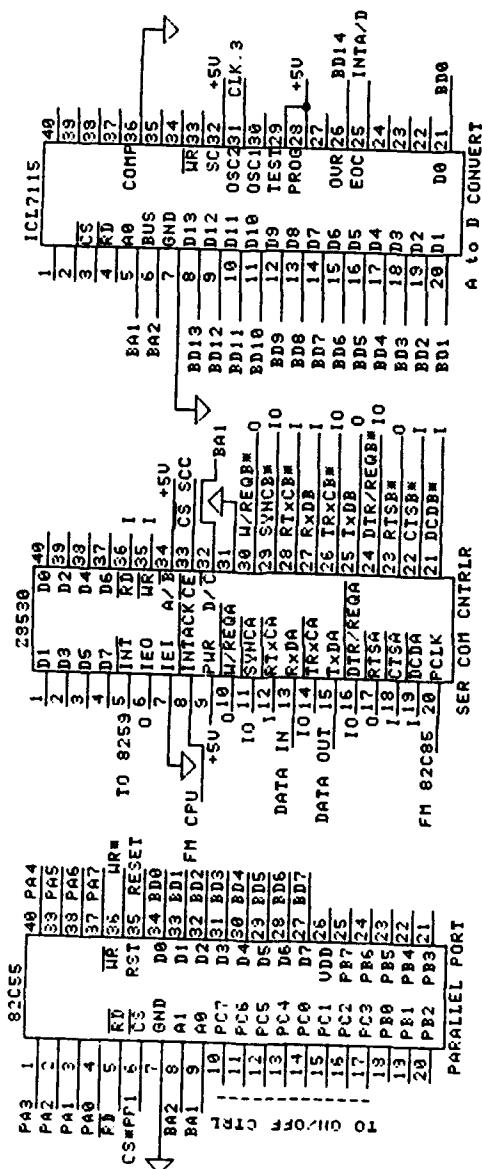


Figure 20. Complete Circuit Schematic--Peripherals

last two pages, in conjunction with Figure 14, constitute the entire computer system in schematic form.

All the components of the system have been shown to work as expected. The oscilloscope has been used to verify correct circuit operation for the complete system.

IV. RECOMMENDATIONS FOR FURTHER WORK

A. WRITE A CHARACTER TO THE CRT

This should be the next step, to verify the capability of correct operation of the SCC within the circuit. The program in Appendix I should give the next person to continue with this open ended project a good base with which to begin.

The following recommended actions are not necessarily in temporal or priority order. However, implementation of this CRT step will be instrumental in the next recommended step.

B. INSTALL HOST-TO-TARGET MONITOR PROGRAM

This will make the job of writing test programs much easier. An assembler or compiler can be used and the program code can be loaded directly to SRAM or into a file which can then be more quickly burned into the EPROM. An assembler could have been used for the present effort, but it was felt that the programs at this level were simple enough that the extra time it would have taken to implement an assembler could be better spent in coding the short programs directly.

C. WRITE OPERATING SYSTEM BOOTSTRAP KERNEL

This assumes that the operating system and application programs should be capable of being loaded from the ground. It is possible, though not likely, that a decision could be

made that all programs will reside in ROM. If so, then SRAM will be used only for messages (and possibly telemetry data).

D. IMPLEMENT AX.25 PROTOCOL

Whether the AX.25 protocol resides in ROM or SRAM, its programming and validation will be an extensive project. There will probably have to be close coordination with the person overseeing the PANSAT communications subsystem at that time.

E. IMPLEMENT RESET

Experience in the laboratory has shown that this is one of the most important required external commands. If the computer system gets hit by a cosmic ray in the wrong place, or otherwise locks up or goes into an invalid state, there must be a way to force the system back to a known state. Hence the need for reset.

F. IDENTIFY OTHER REQUIREMENTS AND BEGIN HARDWARE OR SOFTWARE MODIFICATIONS

A partial list of other possible required tasks on the road to a fully functional flight-ready communications controller and processor are:

- Identify and implement any other required external commands
- Identify and incorporate need, if any, for backup batteries
- Identify any time critical housekeeping tasks
- Identify need for A/D converter and/or parallel port

Instruction Set Summary

APPENDIX A

CONTROL TRANSFER

CALL - CALL

Direct within segment

7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0
1 1 1 0 1 0 0 0	disp low	disp high
1 1 1 1 1 1 1 1	mod 0 1 0	imm
1 0 0 1 1 0 1 0	offset low	offset high
	seg low	seg high
1 1 1 1 1 1 1 1	mod 0 1 1	imm

JMP - Unconditional Jump

Direct within segment

7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0
1 1 1 0 1 0 0 1	disp low	disp high
1 1 1 1 1 1 1 1	disp	
1 1 1 1 1 1 1 1	mod 1 0 0	imm
1 1 1 0 1 0 1 0	offset low	offset high
	seg low	seg high
1 1 1 1 1 1 1 1	mod 1 0 1	imm

RET - Return from CALL

Within segment

7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0	7 6 5 4 3 2 1 0
1 1 0 0 0 0 1 1	data low	data high
1 1 0 0 0 0 1 1		
1 1 0 0 0 0 1 1		
1 1 0 0 0 1 0 0	data low	data high

Jump on equal/zero

Jump on less than greater

or equal

Jump on less or equal/not greater

or equal

Jump on below/above

or equal

Jump on below or equal/not

above

Jump on parity/parity even

Jump on overflow

Jump on sign

Jump on not equal/not zero

Jump on not less/greater

or equal

Jump on not less or equal/not

greater

Mod 1 word instruction

Mod 0 byte instruction

8086 INSTRUCTION SET

JMP/M - Jump on not below/above

or equal

JMP/M - Jump on not below or

equal/above

JNO - Jump on not overflow

JNS - Jump on not sign

LOOP - Loop CX times

LOOPZ/LOOPD - Loop while not

zero/quotient

JCXZ - Jump on CX zero

INT - Interrupt

Type specified

Type 3

INTO - Interrupt on overflow

INT1 - Interrupt return

PROCESSOR CONTROL

CLC - Clear carry

CMC - Complement carry

STC - Set carry

CLD - Clear direction

STD - Set direction

CLI - Clear interrupt

STI - Set interrupt

MUL - Multi

WAIT - Wait

ES - Escape no external device

LOCK - Bus lock probe

Footnotes:

AL = 8-bit accumulator

AX = 16-bit accumulator

CX = Count register

DS = Data segment

ES = Extra segment

Above/below refers to unsigned value

Greater = more positive;

Less = less positive (more negative) signed values

If d = 1 then "to" reg; if d = 0 then "from" reg

If w = 1 then word instruction; if w = 0 then byte instruction

If mod = 11 then r/m is treated as a REG field

If mod = 00 then DISP = 3'; disp-low and disp-high are absent

If mod = 01 then DISP = disp-low sign-extended to 16-bits; disp-high is absent

If mod = 10 then DISP = disp-high; disp-low

If r/m = 000 then EA = (BX) + (SI) - DISP

If r/m = 001 then EA = (BX) + (DI) - DISP

If r/m = 010 then EA = (BP) + (SI) - DISP

If r/m = 011 then EA = (BP) + (DI) - DISP

If r/m = 100 then EA = (SI) - DISP

If r/m = 101 then EA = (DI) - DISP

If r/m = 110 then EA = (BP) - DISP

If r/m = 111 then EA = (BX) - DISP

DISP follows 2nd byte of instruction (before data if required)

*except If mod = 00 and r/m = 110 then EA = disp-high; disp-low

Mnemonics©Intel, 1978

If s/w = 01 then 16 bits of immediate data form the operand

If s/w = 11 then an immediate data byte is sign extended to

form the 16-bit operand

If v = 0 then "count" = 1; if v = 1 then "count" in (CL)

x = don't care

z is used for string primitives for comparison with ZF FLAG

SEGMENT OVERRIDE PREFIX

0 0 1 reg 1 1 0

REG is assigned according to the following table

10:8 (w-1)	8:6 (r-5)	Segment
000 AX	000 AL	00 ES
001 CX	001 CL	01 CS
010 DX	010 DL	10 SS
011 BX	011 BL	11 DS
100 SP	100 AH	
101 BP	101 CH	
110 SI	110 DH	
111 DI	111 BH	

Instructions which reference the flag register file as a 16-bit object use the symbol FLAGS to represent the file

FLAGS = X X X X (OF) (DF) (IF) (TF) (SF) (ZF) X (AF) X (PF) X (CF)

Instruction Set Summary

DATA TRANSFER

	10000000	10000000	10000000	10000000
Register memory to other register	10000000	mod reg imm		
Immediate to register memory	10000000	mod 0 0 imm	data	data d = 1
Immediate to register	10000000	mod 0 imm	data	data d = 1
Memory to destination	10100000	mod imm	mod high	
Accumulator to memory	10100000	mod imm	mod high	
Register memory to segment register	10000000	mod reg imm		
Segment register to register/memory	10000000	mod reg imm		

PUSH - Push

	10000000	mod 1 0 imm
Register	00000000	mod 1 0 imm
Segment register	00000000	mod 1 0 imm

POP - Pop

	10000000	mod 0 0 imm
Register	00000000	mod 0 0 imm
Segment register	00000000	mod 0 0 imm

MOV - Exchange

	10000000	mod reg imm
Register memory with register	10000000	mod reg imm

IN - Input from

	10000000	port
Fixed port	10000000	port
Variable port	10000000	port

OUT - Output to

	10000000	port
Fixed port	10000000	port
Variable port	10000000	port

ADD - Add

	10000000	mod reg imm
Reg memory with register to either	10000000	mod 0 0 imm

IMM - Immediate to either

	10000000	mod 0 0 imm
Immediate to register memory	10000000	mod 0 0 imm

ACC - Load pointer to ACC

	10000000	mod reg imm
ACC - Load ACC to register	10000000	mod reg imm

MOV - Load pointer to DS

	10000000	mod reg imm
MOV - Load pointer to DS	10000000	mod reg imm

MOV - Load pointer to CS

	10000000	mod reg imm
MOV - Load pointer to CS	10000000	mod reg imm

MOV - Store DS into Regs

	10000000	mod reg imm
MOV - Store DS into Regs	10000000	mod reg imm

PUSH - Push Regs

	10000000	mod reg imm
PUSH - Push Regs	10000000	mod reg imm

POP - Pop Regs

	10000000	mod reg imm
POP - Pop Regs	10000000	mod reg imm

ADD - Add with carry

	10000000	mod reg imm
ADD - Add with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

ACC - Acc with carry

	10000000	mod reg imm
ACC - Acc with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
MOV - Move with carry	10000000	mod reg imm

MOV - Move with carry

	10000000	mod reg imm
--	----------	-------------

APPENDIX B

INITIAL CIRCUIT TEST PROGRAM

The program continuously jumps to itself at starting address FFFF0h.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4 FF	1FFFA	_____	;Jmp to FFFF0
FFFF3 FF	1FFF9	_____	;
FFFF2 00	1FFF9	_____	;
FFFF1 00	1FFF8	_____	;
FFFF0 EA	1FFF8	_____	; <---(Pwr on rst jmp)

APPENDIX C

INITIAL MEMORY TEST PROGRAM

Program continuously writes the arbitrary number "5" to arbitrary SRAM memory location BFFF0.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA	— ;Jmp to FFFFDC
FFFF3	FD	1FFF9	— ;
FFFF2	00	1FFF9	— ;
FFFF1	0C	1FFF8	— ;
FFFF0	EA	1FFF8	— ;<---(Pwr on rst jmp)
FFFFE	FF	1FFF7	1FFF7 — ;Jmp to BFFF0
FFFEE	FF	1FFF7	— ;
FFFED	00	1FFF6	— ;
FFFEC	00	1FFF6	— ;
FFFEB	EA	1FFF5	— ;
FFFEA	14	1FFF5	— ;Mov B fm M[BFFF0] to DL ;register
FFFE9	8A	1FFF4	1FFF4 — ;
FFFE8	90	1FFF4	— ;NOP
FFFE7	05	1FFF3	1FFF3 — ;Mov B immed #05 to ;M[BFFF0] ;(M[BFFFx4 + 0 = BFFF0])
FFFE6	04	1FFF3	— ;
FFFE5	C6	1FFF2	1FFF2 — ;Mov W immed #0000 to SI ;register
FFFE4	00	1FFF2	— ;
FFFE3	00	1FFF1	1FFF1 — ;
FFFE2	BE	1FFF1	— ;
FFFE1	DE	1FFF0	1FFF0 — ;Mov W SI reg to DS seg ;register
FFFE0	8E	1FFF0	— ;
FFFDF	BF	1FFEF	1FFEF — ;Mov W immed #BFFF to SI ;register
FFFDE	FF	1FFEF	— ;
FFFDD	C6	1FFEE	1FFEE — ;
FFFDC	C7	1FFEE	— ;

APPENDIX D

MEMORY/IO TEST PROGRAM

Program to verify that the CPU asserts IO* of the M/IO* signal when writing to a variable port--in this case pin 10 (Y5) on the IO chip select Decoder. It was written because the program to load the 82C53 (cheap prototype replacement for the 82C54) with a control word (Mode 3) and an initial count (04) didn't appear to be working. To eliminate the M/IO* select circuitry as the culprit, this program tests to make sure IO* is asserted when OUT writes to a variable port. The proper chip select line is asserted.

8086	LO	HI	
ADDR	BYTE	BYTE	
	EPROM	EPROM	
	ADDR	ADDR	
FFFF4 FF	1FFFA		;Jmp to FFFE8
FFFF3 F0	1FFF9		;
FFFF2 00	1FFF9		;
FFFF1 E8	1FFF8		;
FFFF0 EA	1FFF8		; <---(Pwr on rst jmp)
FFFFE EF	1FFF7		1FFF7 ;OUT to [port DX] with
			;(AL)
FFFEE FF	1FFF7		;Load AL with #FF
FFFED C0	1FFF6		;
FFFEC C6	1FFF6		;
FFFEB 02	1FFF5		1FFF5 ;Load DX with #0280 (Port
			;"5")
FFFEA 80	1FFF5		;A11A10A9A8A7A6A5A4A3A2A1A0
FFFEB C2	1FFF4		1FFF4 ; X 0 1 0 1 X X X X 0 0 X
			;
			2 8 0
FFFE8 C7	1FFF4		;

Line Y5 is asserted, as expected, when IO* of M/IO* is asserted.

APPENDIX E

INITIAL 82C54 TIMER TEST PROGRAM

The program loads the 82C54 (or '53) timer (counter 2) with a control word (byte) indicating mode 3 (square wave generator) with a period loaded as an initial count, in this case "4". The timer's cycle, therefore, is 1/4 of the input clock's, or 1/4 of 0.3125 MHz = 78.125 kHz.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4 FF	1FFFA		;Jmp to FFFDB
FFFF3 F0		1FFF9	;
FFFF2 00	1FFF9		;
FFFF1 DB		1FFF8	;
FFFF0 EA	1FFF8		<---(Pwr on rst jmp)
FFFFE9 FF		1FFF7	1FFF7 ;Jmp to FFFEB-->
FFFEE F0	1FFF7		;Continuous loop--
FFFED 00		1FFF6	;timer set
FFFEC EB (DB)	1FFF6		; (Jmp to FFFDB-keep
FFFEB EA		1FFF5	;setting the timer,
FFFEA EE	1FFF5		;over and over)
FFFE9 02		1FFF4	1FFF4 ;OUT to [DX port] with
FFFE8 7C	1FFF4		; (AL=04)--port addr
FFFE7 C2		1FFF3	; is Y4 (Timer)
			1FFF3 ;Load cntr 2 with init
			;count
		1FFF4	1FFF4 ;Load DX with #027C*
			;A11A10A9A8A7A6A5A4A3A2A1A0
		1FFF3	1FFF3 ; X 0 1 0 0 X X X X 1 0 X
			;
			2 7 C
			;Port Y4, load into cntr
			;2 init value (in AL)
FFFE6 C7	1FFF3		1FFF2 ;
FFFE5 04		1FFF2	1FFF2 ;Load AL with #04*
FFFE4 C0	1FFF2		; (Initial counter value)
FFFE3 C6		1FFF1	1FFF1 ;
FFFE2 EE	1FFF1		1FFF1 ;OUT to [DX port] with
			; (AL = 96)--Control word
			; (AL) selects cntr 2,
			1FFF1 ;Mode 3

FFFE1	96	1FFF0	;Load AL with #96*	
FFFE0	C0	1FFF0	;Cntr 2, LSB, Mode3, ;Binary cnt	
FFFDF	C6	1FFE F	;	
FFFDE	02	1FFE F	;Load DX with #027E*	
FFFDD	7E	1FFEE	;A11A10A9A8A7A6A5A4A3A2A1A0	
FFFDC	C2	1FFEE	; 0 0 1 0 0 X X X X 1 1 X	
			;	
			; 2 7 E	
			;Port Y4 (Timer), write	
			;cntrl "word" (to come	
FFFDB	C7	1FFED E	;from AL)	

26 bytes

*The 2 byte opcode loads of DX (C7 C2) and AL (C6 C0) can be replaced by the 1 byte opcodes BA and B0, respectively.

APPENDIX F

INTRRPT CNTRLR TEST PROGRAM: INCREMENT 1

This program only tests the 8254 timer in mode 0 as a prelude to the full-blown interrupt controller test program (iteration 3).

First, it was verified that the timer could be programmed to time out and go high while the CPU was doing a loop for a certain number of iterations. The address and data lines and the timing relationships were as expected.

The data sheet on the 8254 timer is wrong. It said that once the timer times out in Mode 0, one needs only to reload the CW or reload the count and the timer will resume counting. Evidently, one needs to reload both the CW and the initial count, as in this program, for the counter to resume counting.

The code is read from bottom to top.

8086	LO	HI	
ADDR	BYTE	BYTE	
	EPROM	EPROM	
	ADDR	ADDR	
FFFF4	FF	1FFFA	_____ ;Jmp to FFFCA
FFFF3	F0	1FFF9	_____ ;
FFFF2	00	1FFF9	_____ ;
FFFF1	CA	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF	FF	1FFF7	_____ ;Jmp to FFFD6
FFFEE	F0	1FFF7	_____ ;(Reset timer after AX
FFFED	00	1FFF6	_____ ;counts down from 127d)
FFFEC	D6	1FFF6	_____ ;
FFFEB	EA	1FFF5	_____ ;
FFFEA	EE	1FFF5	_____ ;Write init cnt (02) to
FFFE9	02	1FFF4	_____ ;timer; Load AL with init
FFFE8	B0	1FFF4	_____ ;count = 02
FFFE7	02	1FFF3	_____ ;Move #0204 to DX reg
FFFE6	04	1FFF3	_____ ;Cntr 2 is to be loaded
FFFE5	BA	1FFF2	_____ ;with initial count
FFFE4	EE	1FFF2	_____ ;Write cntrl W (90) to
FFFE3	90	1FFF1	_____ ;timer
FFFE2	B0	1FFF1	_____ ;Load AL with CW = 90
			_____ ;(Mode 0, LSB, cntr 2)

FFFE1	02	1FFF0	;Move #0206 to DX ;register
FFFE0	06	1FFF0	;The CW in AL is to be
FFFDF	BA	1FFE9	written to the cntr 2 CW ;register
FFFDE	F9	1FFE9	;Else, Short Jump to ;FFFDB to decrement
FFFDD	EB	1FFEE	1FFEE____;AX again (F9 = -7d) ;If AX = 0, jump 2
FFFDC	02	1FFEE	1FFED____;addresses, to FFFDF ;CMP AX with 0
FFFDB	74	1FFED	1FFEC____; ;Decrement AX
FFFDA	00	1FFEC	1FFEB____;Load AX with 127d ____; ;OUT initial count to
FFFD9	3C	1FFEC	1FFEA____;counter 2 ;Load initial count of 2
FFFD8	48	1FFEB	1FFE9____;into AL ;Load DX with #0204 for
FFFD7	7F	1FFEB	1FFE8____;timer initial count ____;(from AL to be loaded)
FFFD6	B0	1FFEB	1FFE7____;OUT the CW to the timer ;Load the CW for Mode 0, 1FFE6____;LSB, counter 2 into AL ;Ld DX with #0206 for 1FFE5____;selecting timer, write ____;CW (with CW in AL)
FFFD5	EE		
FFFD4	02		
FFFD3	B0		
FFFD2	02		
FFFD1	04		
FFFD0	BA		
FFFCF	EE		
FFFCF	90		
FFFCF	B0		
FFFCF	02		
FFFCF	06		
FFFCF	BA		

43 bytes

APPENDIX G

INTRPT CNTRLR TEST PROGRAM: INCREMENT 2

In step one, it was verified that the timer could be programmed to run in Mode 0. When *OUT2* on the 8254 went high it stayed high until the timer was reset. The timer was reset only after the CPU looped for a large number of iterations. When the CPU was done, it reset the timer and the process was continually repeated.

In this iteration, when the timer times out, *OUT2* is used as a signal to the 8259 on *IR3* that there is an interrupt to be serviced. The 8259 alerts the CPU with the *INT* line. The CPU replies with *INTA** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself have to have been first loaded into memory.) The ISR just resets the timer.

The code is read from bottom to top.

8086	LO	HI	
ADDR	BYTE	BYTE	
	EPROM	EPROM	
	ADDR	ADDR	
FFFF4	FF	1FFFA	_____ ;Jmp to FFF61
FFFF3	F0	1FFF9	_____ ;
FFFF2	00	1FFF9	_____ ;
FFFF1	61	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF	FF	1FFF7	_____ ;Jmp to FFFEB
FFFEE	F0	1FFF7	_____ ;The CPU stays here until
FFFED	00	1FFF6	_____ ;it's interrupted
FFFEC	EB	1FFF6	_____ ;
FFFEB	EA	1FFF5	_____ ;
FFFEA	FB	1FFF5	_____ ;Enable interrupts

Load the interrupt service routine. The ISR resets the timer and clears the highest priority ISR bit in the 8259 (there is only one in this case). Because the 8259 runs at 2.5 MHz and the timer only runs at .3125 MHz, there is a little delay loop to make sure the timer has gone low after being reset before the ISR bit is reset and interrupts are again enabled.

The delay loop is almost certainly not required, but it doesn't hurt to have it.

FFFE9	CF	1FFF4	1FFF4	;Code CF-->return from
FFFE8	FB	1FFF4	1FFF4	;ISR; Code FB-->Enable
FFFE7	05	1FFF3	1FFF3	;interrupts
FFFE6	C7	1FFF3	1FFF3	_____;
FFFE5	47	1FFF2	1FFF2	_____;
FFFE4	47	1FFF2	1FFF2	_____;
FFFE3	EE	1FFF1	1FFF1	;Code EE-->OUT to reset
				;ISR bit
FFFE2	20	1FFF1	1FFF1	;Code B0 20-->Load AL
				;with 20 ("20" for OCW2
FFFE1	05	1FFF0	1FFF0	;will reset highest
FFFE0	C7	1FFF0	1FFF0	;priority ISR bit)
FFFDF	47	1FFEF	1FFEF	_____;
FFFDE	47	1FFEF	1FFEF	_____;
FFFDD	B0	1FFEE	1FFEE	;Code BA 00 01-->Load DX
FFFDC	01	1FFEE	1FFEE	;with addr to write OCW2
FFFDB	05	1FFED	1FFED	;to 8259 to reset ISR bit
FFFDA	C7	1FFED	1FFED	;for IR3; (OUT2 has had
				;plenty of time to go low
				;because AX counted down
FFFD9	47	1FFEC	1FFEC	_____;from 8)
FFFD8	47	1FFEC	1FFEC	_____;
FFFD7	00	1FFEB	1FFEB	_____;
FFFD6	BA	1FFEB	1FFEB	_____;
FFFD5	05	1FFEA	1FFEA	_____;
FFFD4	C7	1FFEA	1FFEA	_____;
FFFD3	47	1FFE9	1FFE9	_____;
FFFD2	47	1FFE9	1FFE9	_____;
FFFD1	F9	1FFE8	1FFE8	;Code EB 49-->Jump back 7
FFFD0	EB	1FFE8	1FFE8	;counts to opcode 48 to
FFFCF	05	1FFE7	1FFE7	;decrement AX again
FFFCF	C7	1FFE7	1FFE7	_____;
FFFCF	47	1FFE6	1FFE6	_____;
FFFCB	02	1FFE6	1FFE6	_____;
FFFCB	74	1FFE5	1FFE5	;Code 74 02-->If AX was 0
FFFCB	05	1FFE5	1FFE5	;then jump forward 2
FFFC8	C7	1FFE4	1FFE4	;counts to BA opcode;
FFFC7	47	1FFE4	1FFE4	;else, go to next opcode:
FFFC6	47	1FFE3	1FFE3	;EB
FFFC5	00	1FFE3	1FFE3	_____;
FFFC4	3C	1FFE2	1FFE2	;Code 3C 00-->CMP AX with
FFFC3	05	1FFE1	1FFE1	;0
FFFC2	C7	1FFE1	1FFE1	_____;
FFFC1	47	1FFE0	1FFE0	_____;
FFFC0	47	1FFE0	1FFE0	_____;

FFFFBF	48	1FFDF	1FFDF	;Code B0 08--Load AL with ;8	
FFFBE	08	1FFDF	1FFDE	;Code 48-->Decrement AX	
FFFBD	05	1FFDE	1FFDD	_____;	
FFFBC	C7	1FFDE	1FFDD	_____;	
FFFBB	47	1FFDD	1FFDC	_____;	
FFFBA	47	1FFDD	1FFDC	;Code EF-->OUT with ;initial count to	
FFFBB9	B0	1FFDC	1FFDB	;cntr 2	
FFFBB8	EF	1FFDC	1FFDA	_____;	
FFFBB7	05	1FFDB	1FFDA	_____;	
FFFBB6	C7	1FFDB	1FFD9	_____;	
FFFBB5	47	1FFDA	1FFD9	;Code B8 2F 00-->load AX ;with 00 2F as initial	
FFFBB4	47	1FFDA	1FFD8	1FFD8	;count
FFFBB3	00	1FFD9	1FFD7	_____;	
FFFBB2	2F	1FFD9	1FFD7	_____;	
FFFBB1	05	1FFD8	1FFD6	;Code BA 04 02-->Load DX ;with addr to load the	
FFFBB0	C7	1FFD8	1FFD5	;cntr 2 with the initial ;word size count (from	
FFFBAF	47	1FFD7	1FFD4	;AX)	
FFFBAE	47	1FFD7	1FFD4	_____;	
FFFAD	B8	1FFD6	1FFD3	_____;	
FFFAC	02	1FFD6	1FFD2	_____;	
FFFAB	05	1FFD5	1FFD1	_____;	
FFFAA	C7	1FFD5	1FFD1	;DI = 5	
FFFBA9	47	1FFD4	1FFD0	;Code B0 B0-->load AL	
FFFBA8	47	1FFD4	1FFD0	;with cntr 2 CW, Mode 0,	
FFFBA7	04	1FFD4	1FFCF	;word size initial count	
FFFBA6	BA	1FFD3	1FFCF	_____;	
FFFBA5	05	1FFD3	1FFCF	;Code EE-->WR the CW B0	
FFFBA4	C7	1FFD2	1FFCF	;to AL)	
FFFBA3	47	1FFD2	1FFCE	_____;	
FFFBA2	47	1FFD1	1FFCE	;DI = 4	
FFFBA1	EE	1FFD1	1FFCD	_____;	
FFFBA0	B0	1FFD0	1FFCD	;Move code "02 B0" to	
FFF9F	05	1FFD0	1FFCD	;M[DS + DI] ; = M[40002]	
FFF9E	C7	1FFCF	1FFCC	;Code "BA 06 02"-->Load	
FFF9D	47	1FFCF	1FFCC	;DX with addr where to ld	
FFF9C	47	1FFCE	1FFCC	;AL cntr 2 CW	
FFF9B	B0	1FFCE	1FFCB	_____;	
FFF9A	02	1FFCD	1FFCB	;Increment DI-->DI = 2	
FFF99	05	1FFCD	1FFCB	_____;	
FFF98	C7	1FFCC	1FFCA	;Increment DI-->DI = 1	
FFF97	47	1FFCC	1FFCA	_____;	
FFF96	47	1FFCB	1FFCA	;Move code "BA 06" to [DS	
FFF95	06	1FFCB	1FFCA	;+ DI = M[4000(0)]	
FFF94	BA	1FFCA	1FFC9	_____;	
FFF93	05	1FFCA	1FFC9	_____;	
FFF92	C7	1FFC9	1FFC8	_____;	
FFF91	00	1FFC9	1FFC8	;Move 00 00 TO DI reg	

FFF90	00	1FFC8	;
FFF8F	BF	1FFC7	_____;
FFF8E	D8	1FFC7	;Move (AX) to DS reg
FFF8D	8E	1FFC6	_____;
FFF8C	40	1FFC6	;Load AX with 40 00
FFF8B	00	1FFC5	_____;
FFF8A	B8	1FFC5	_____;

Load the address of the ISR in the location for external interrupt number 3 (0008C to 0008F) and initialize the stack segment and the stack pointer.

FFF89	FF	1FFC4	_____ ;Move FF FF to SP
FFF88	FF	1FFC4	_____ ;
FFF87	BC	1FFC3	_____ ;Move (AX) to SS reg
FFF86	D0	1FFC3	_____ ;
FFF85	8E	1FFC2	_____ ;Load AX with 50 00
FFF84	50	1FFC2	_____ ;
FFF83	00	1FFC1	_____ ;
FFF82	B8	1FFC1	_____ ;
FFF81	40	1FFC0	_____ ;Move 40 00 to EA = ;[DS + DI] = [0 + 8E]
FFF80	00	1FFC0	_____ ;(CS = 4000(0), IP = ;0000; ISR addr loaded)
FFF7F	05	1FFBF	_____ ;
FFF7E	C7	1FFBF	_____ ;Move 00 8E to DI reg
FFF7D	00	1FFBE	_____ ;
FFF7C	8E	1FFBE	_____ ;
FFF7B	BF	1FFBD	_____ ;Move 00 00 to EA = ;[DS + DI] = [0 + 8C]
FFF79	00	1FFBD	_____ ;(IP for ISR = 0000)
FFF78	05	1FFBC	_____ ;
FFF77	C7	1FFBC	_____ ;Move 00 8C to DI reg
FFF76	00	1FFBB	_____ ;(ISR addr will be at ;0008C through 0008F)
FFF75	8C	1FFBA	_____ ;
FFF74	BF	1FFBA	_____ ;Move AX to DS register
FFF73	D8	1FFB9	_____ ;
FFF72	8E	1FFB9	_____ ;Load AX with 00 00
FFF71	00	1FFB8	_____ ;
FFF70	00	1FFB8	_____ ;
FFF6F	B8	1FFB7	_____ ;

Initialize the 82C54 timer for counter 2, Mode 0, with an initial count of FF FF. This should be plenty of time for the ISR address and the ISR itself above to be completely loaded before the timer times out.

FFF6E	EF	1FFB7	_____ ;LSB, then MSB to cntr 2
FFF6D	FF	1FFB6	_____ ;Load initial count, FF
FFF6C	FF	1FFB6	_____ ;FF, into AX
FFF6B	B8	1FFB5	_____ ;

FFF6A	02	1FFB5		;Load DX with address for
FFF69	04		1FFB4	;cntr 2 initial count (to
FFF68	BA	1FFB4	_____	;come from AX)
FFF67	EE		1FFB3	_____ ;CW to cntr 2
FFF66	B0	1FFB3		;Load CW in AL = B0
FFF65	B0		1FFB2	; (Mode 0,16 bit cnt,
			_____	;cntr 2)
FFF63	02	1FFB2		;Load DX with "address"
FFF62	06		1FFB1	;for counter 2 CW (to
FFF61	BA	1FFB1	_____	;come from AL)

148 bytes

APPENDIX H

INTRPT CNTRLR TEST PROGRAM: INCREMENT 3

(Correct operation of this program could not be validated.)

In this iteration, as in the second iteration, when the timer times out, *OUT2* is used as a signal to the 8259 on *IR3* that there is an interrupt to be serviced. The 8259 alerts the CPU with the *INT* line. The CPU replies with *INTA** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself have to have been first loaded into memory.)

The difference of this iteration is that the ISR first puts out the byte, previously stored at memory location 40000, to the serial communications controller (SCC). Next, the ISR resets the timer, loops for a short while to give the timer more than enough time to go low, and then resets the 8259. When the timer times out, the ISR is run again. One sees the letter "A" on the SCC data pins every 79, 8254 clock cycles. Each 8254 clock cycle takes 16 system or CPU clock cycles (5MHz) to complete. Thus, one sees the "A" approximately every $79 \times 16 \times 200$ nanoseconds = 252.8 microseconds. Actually, it takes a little bit longer than this due to the overhead time required to reset the timer.

The code is read from bottom to top.

		LO	HI	
8086		BYTE	BYTE	
ADDR		EPROM	EPROM	
		ADDR	ADDR	
FFFF4	FF	1FFFA		;Jmp to FFF30
FFFF3		F0	1FFF9	;
FFFF2	00		1FFF9	;
FFFF1	30		1FFF8	;
FFFF0	EA		1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF		FF	1FFF7	;Jmp to FFFEB
FFFEE	F0		1FFF7	;The CPU stays here until
FFFED		00	1FFF6	;it's interrupted
FFFEC	EB		1FFF6	;
FFFEB	EA		1FFF5	_____ ;
FFFEA	FB		1FFF5	_____ ;Enable interrupts

Load the interrupt service routine. The ISR first puts out the byte from memory location 40000 to the SCC. Then it resets the timer and clears the highest priority ISR bit in the 8259 (there is only one in this case). Because the 8259 runs at 2.5 MHz and the timer only runs at .3125 MHz, there is a little delay loop to make sure the timer has gone low after being reset before the ISR bit is reset and interrupts are again enabled. The delay loop is almost certainly not required, but it doesn't hurt to have it.

FFFE9	CF	1FFF4	;Code CF-->return from ;ISR
FFFE8	FB	1FFF4	;Code FB-->Enable ;interrupts
FFFE7	05	1FFF3	;
FFFE6	C7	1FFF3	;
FFFE5	47	1FFF2	;
FFFE4	47	1FFF2	;
FFFE3	EE	1FFF1	;Code EE-->OUT to reset ;ISR bit
FFFE2	20	1FFF1	;Code B0 20-->Load AL
FFFE1	05	1FFF0	;with 20 ("20" for OCW2
FFFE0	C7	1FFF0	;will reset highest ;priority ISR bit)
FFFDF	47	1FFEF	;
FFFDE	47	1FFEF	;
FFFDD	B0	1FFEE	;Code BA 00 01-->Load DX
FFFDC	01	1FFEE	;with addr to write OCW2
FFFDB	05	1FFED	;to 8259 to reset ISR bit
FFFDA	C7	1FFED	;for IR3; (OUT2 has had ;plenty of time to go low ;because AX counted down ;from 8)
FFFD9	47	1FFEC	;
FFFD8	47	1FFEC	;
FFFD7	00	1FFEB	;
FFFD6	BA	1FFEB	;
FFFD5	05	1FFEA	;
FFFD4	C7	1FFEA	;
FFFD3	47	1FFE9	;
FFFD2	47	1FFE9	;
FFFD1	F9	1FFE8	;Code EB 49-->Jump back 7
FFFD0	EB	1FFE8	;counts to opcode 48 to
FFFCF	05	1FFE7	;decrement AX again
FFFCF	C7	1FFE7	;
FFFCF	47	1FFE6	;
FFFCF	47	1FFE6	;
FFFCB	02	1FFE5	;Code 74 02-->If AX was 0
FFFCB	74	1FFE5	;then jump forward 2
FFFC9	05	1FFE4	;counts to BA opcode;

FFFC7	47	1FFE3	1FFE3 _____;
FFFC6	47	1FFE3	1FFE3 _____;
FFFC5	00	1FFE2	1FFE2 ;Code 3C 00-->CMP AX with
FFFC4	3C	1FFE2	0 ;0
FFFC3	05	1FFE1	1FFE1 _____;
FFFC2	C7	1FFE1	1FFE0 _____;
FFFC1	47	1FFE0	1FFE0 _____;
FFFC0	47	1FFE0	1FFDF ;Code B0 08--Load AX with
FFFBF	48	1FFDF	8 ;8
FFFBE	08	1FFDF	1FFDE ;Code 48-->Decrement AX
FFFBD	05	1FFDE	1FFDD _____;
FFFBC	C7	1FFDE	1FFDD _____;
FFFBB	47	1FFDD	1FFDD _____;
FFFBA	47	1FFDD	1FFDC ;Code EF-->OUT with
FFFB9	B0	1FFDC	initial count to
FFFB8	EF	1FFDC	1FFDB ;cntr 2
FFFB7	05	1FFDB	1FFDA _____;
FFFB6	C7	1FFDB	1FFDA _____;
FFFB5	47	1FFDA	1FFD9 ;Code B8 2F 00-->load AX
FFFB3	00	1FFD9	with 00 4F as initial
FFFB2	4F	1FFD9	1FFD8 ;count
FFFB1	05	1FFD8	1FFD7 _____;
FFFB0	C7	1FFD8	1FFD6 ;Code BA 04 02-->Load DX
FFFAF	47	1FFD7	with addr to load the
FFFAE	47	1FFD7	1FFD5 ;cntr 2 with the initial
FFFAF	B8	1FFD6	word size count (from
FFFAA	C7	1FFD5	;AX)
FFFA9	47	1FFD4	1FFD4 _____;
FFFA8	47	1FFD4	1FFD3 _____;
FFFA7	04	1FFD3	1FFD3 _____;
FFFA6	BA	1FFD3	1FFD2 _____;
FFFA5	05	1FFD2	1FFD1 _____;
FFFA4	C7	1FFD2	1FFD0 ;Code B0 B0-->load AL
FFFA3	47	1FFD1	with cntr 2 CW, Mode 0,
FFFA2	47	1FFD1	1FFCF ;word size initial count
FFFA1	EE	1FFD0	Code EE-->WR the CW B0
FFFA0	B0	1FFD0	to AL)
FFF9F	05	1FFCF	1FFCE _____;
FFF9E	C7	1FFCF	1FFCD ;Code BA 06 02-->Load DX
FFF9D	47	1FFCE	with addr for cntr 2 CW
FFF9C	47	1FFCE	1FFCC ;(from AL)
FFF9B	B0	1FFCE	1FFCC _____;
FFF9A	02	1FFCD	1FFCB _____;
FFF99	05	1FFCD	
FFF98	C7	1FFCC	
FFF97	47	1FFCC	

FFF96	47	1FFCB	1FFCA	;
FFF95	06	1FFCA	1FFCA	;
FFF94	BA	1FFCA	1FFC9	;
FFF93	05	1FFC9	1FFC9	;
FFF92	C7	1FFC9	1FFC9	;
FFF91	47	1FFC8	1FFC8	;
FFF90	47	1FFC8	1FFC7	;
FFF8F	EE	1FFC7	1FFC7	;Code BA 02 00-->
FFF8E	00	1FFC7	1FFC6	;Load DX with 0200--
FFF8D	05	1FFC7	1FFC6	;"addr" of the SCC port
FFF8C	C7	1FFC6	1FFC5	;
FFF8B	47	1FFC5	1FFC5	Code EE-->(AL) to SCC
FFF8A	47	1FFC5	1FFC4	;
FFF89	02	1FFC4	1FFC4	;
FFF88	BA	1FFC4	1FFC3	;
FFF87	05	1FFC3	1FFC3	;
FFF86	C7	1FFC3	1FFC2	;
FFF85	47	1FFC2	1FFC2	;
FFF84	47	1FFC2	1FFC1	;
FFF83	05	1FFC1	1FFC1	;Code 8A 05-->
FFF82	8A	1FFC1	1FFC0	;Move "A" at M[40000]
FFF81	05	1FFC1	1FFC0	;to AL register
FFF80	C7	1FFC0	1FFBF	;
FFF7F	47	1FFC0	1FFBF	;
FFF7E	47	1FFBF	1FFBF	;
FFF7D	00	1FFBF	1FFBE	;
FFF7C	00	1FFBE	1FFBE	;Code BF 00 00-->
FFF7B	05	1FFBE	1FFBD	;Load DI with 0000
FFF7A	C7	1FFBD	1FFBD	;
FFF79	47	1FFBD	1FFBC	;
FFF78	47	1FFBC	1FFBC	;
FFF77	BF	1FFBC	1FFBB	;
FFF76	D8	1FFBC	1FFBB	;Move D8 BF to 40005
FFF75	05	1FFBB	1FFBA	;Code 8E D8-->Move (AX)
FFF74	C7	1FFBA	1FFBA	;to DS register
FFF73	47	1FFBA	1FFB9	;
FFF72	47	1FFB9	1FFB9	;Inc DI
FFF71	8E	1FFB9	1FFB8	;
FFF70	40	1FFB8	1FFB8	;Move code "40 8E" to
FFF6F	05	1FFB8	1FFB7	;M[40003];
FFF6E	C7	1FFB7	1FFB7	;Code B8 00 40-->Load
FFF6D	47	1FFB7	1FFB6	;AX with 4000
FFF6C	47	1FFB6	1FFB6	;
FFF6B	00	1FFB6	1FFB5	;Inc DI-->DI = 3
FFF6A	B8	1FFB5	1FFB5	;
FFF69	05	1FFB4	1FFB4	;Inc DI-->DI = 2
FFF68	C7	1FFB4	1FFB3	;
FFF67	00	1FFB4	1FFB3	;Move code "B8 00" to
FFF66	01	1FFB3	1FFB2	;M[4000x4 + 1] = 40001
FFF65	BF	1FFB3	1FFB2	;
FFF64	D8	1FFB2	1FFBF	;

FFF63	8E	1FFB1	_____;
FFF62	40	1FFB1	;Load AX with 40 00
FFF61	00	1FFB0	_____;
FFF60	B8	1FFB0	_____;

Load the address of the ISR in the location for external interrupt number 3 (0008C to 0008F) and initialize the stack segment and the stack pointer.

FFF5F	FF	1FFAF	_____ ;Move FF FF to SP
FFF5E	FF	1FFAF	_____ ;
FFF5D	BC	1FFAE	_____ ;
FFF5C	D0	1FFAE	;Move (AX) to SS reg
FFF5B	8E	1FFAD	_____ ;
FFF5A	50	1FFAD	;Load AX with 50 00
FFF59	00	1FFAC	_____ ;
FFF58	B8	1FFAC	_____ ;
FFF57	40	1FFAB	;Move 40 00 to EA = ;[DSx4 + DI] = [0 + 8E]
FFF56	00	1FFAB	1FFAA ;(CS = 4000(0), IP =
FFF55	05	1FFAA	_____ ;0001; ISR addr loaded)
FFF54	C7	1FFAA	1FFA9 ;Move 00 8E to DI reg
FFF53	00	1FFA9	_____ ;
FFF52	8E	1FFA9	1FFA8 _____ ;
FFF51	BF	1FFA8	;Move 01 00 to EA = ;[DSx4 + DI] = [0 - 8C]
FFF50	00	1FFA8	1FFA7 ;(IP for ISR = 0001)
FFF4F	01	1FFA7	1FFA6 _____ ;
FFF4E	05	1FFA7	;Move 00 8C to DI reg
FFF4D	C7	1FFA6	1FFA5 ;(ISR addr will be at
FFF4C	00	1FFA6	_____ ;0008C through 0008F)
FFF4B	8C	1FFA5	1FFA4 ;Move AX to DS register
FFF4A	BF	1FFA5	_____ ;
FFF49	D8	1FFA4	1FFA3 ;Load AX with 00 00
FFF48	8E	1FFA4	1FFA2 _____ ;
FFF47	00	1FFA3	
FFF46	00	1FFA3	
FFF45	B8	1FFA2	

Initialize the 82C54 timer for counter 2, Mode 0, with an initial count of FF FF. This should be plenty of time for the ISR address and the ISR itself above to be completely loaded before the timer times out the first time.

FFF44	EF	1FFA2	_____ ;LSB, then MSB to cntr 2
FFF43	FF	1FFA1	;Load initial count, FF
FFF42	FF	1FFA1	;FF, into AX
FFF41	B8	1FFA0	_____ ;
FFF40	02	1FFA0	;Load DX with address for
FFF3F	04	1FF9F	;cntr 2 initial count (to

FFF3E	BA	1FF9F	_____ ;come from AX)
FFF3D	EE	1FF9E	_____ ;CW to cntr 2
FFF3C	B0	1FF9E	_____ ;Load CW in AL = B0
FFF3B	B0	1FF9D	_____ ;(Mode 0,16 bit cnt, _____ ;cntr 2)
FFF3A	02	1FF9D	_____ ;Load DX with "address"
FFF39	06	1FF9C	_____ ;for counter 2 CW (to
FFF38	BA	1FF9C	_____ ;come from AL)

Load the character "A" into memory location [40000].

FFF37	C1	1FF9B	1FF9B _____ ;Write "A" to [DSx4 + DI _____ ;= 40000] ("A" =
FFF36	05	1FF9B	1FF9A _____ ;11000001)
FFF35	C6	1FF9A	1FF99 _____ ;Move AX to DS
FFF34	D8	1FF9A	1FF98 _____ ;Move #4000 to AX
FFF33	8E	1FF99	1FF98 _____ ;
FFF32	40	1FF99	1FF98 _____ ;
FFF31	00	1FF98	1FF98 _____ ;
FFF30	B8	1FF98	1FF98 _____ ;

197 bytes

APPENDIX I

SERIAL COMMUNICATIONS CONTROLLER TEST PGM

First, memory is loaded with the arbitrary character "A." Then the SCC is initialized. The CPU then goes into a loop where it puts out the "A" from memory to the SCC Tx buffer and checks to see if the Tx buffer is empty. It keeps polling the Tx buffer until it is empty. Then the CPU fetches the "A" from memory again and the process repeats. For this test, the timer and the 8259 are not used.

The code is read from bottom to top.

8086	LO	HI	
ADDR	BYTE	BYTE	
	EPROM	EPROM	
	ADDR	ADDR	
FFFF4	FF	1FFFA	_____ ;Jmp to FFFA5
FFFF3	F0	1FFF9	_____ ;to begin program
FFFF2	00	1FFF9	_____ ;
FFFF1	A5	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on·rst jmp)
FFFEF	FF	1FFF7	_____ ;Jmp to read character
FFFEE	F0	1FFF7	_____ ;from memory again
FFFED	00	1FFF6	_____ ;(Tx buffer empty)
FFFEC	CD	1FFF6	_____ ;
FFFEB	EA	1FFF5	_____ ;
FFFEA	FF	1FFF5	_____ ;Jump to read RR0 again;
FFFE9	F0	1FFF4	_____ ;Tx buffer not yet empty
FFFE8	00 (CD)	1FFF4	_____ ;(CD-->Put out the char
FFFE7	DB	1FFF3	_____ ;from memory, anyway)
FFFE6	EA	1FFF3	_____ ;
FFFE5	05	1FFF2	_____ ;If Tx buffer empty, skip
FFFE4	74	1FFF2	_____ ;next JMP statement
FFFE3	44	1FFF1	_____ ;Compare AL with #44
FFFE2	3C	1FFF1	_____ ;AL = 44 if Tx empty
FFFE1	EC	1FFF0	_____ ;Read byte in RR0-->(AL)
FFFE0	EE	1FFF0	_____ ;Tell WR0 what reg to
FFDFE	00	1FFEF	_____ ;read
FFDDE	B0	1FFEF	_____ ;Load AL with 00->The reg
FFDDC	00	1FFEE	_____ ;to be read is RR0
FFDDB	BA	1FFEE	_____ ;Load DX for SCC CS* and
		1FFED	_____ ;to read (or write) a CW

The character at [40000] is put out to the SCC to be automatically transmitted at 9600 baud.

FFFDA	EE	1FFED	_____	;OUT the data ("A") to ;the SCC
FFFD9	00	1FFEC	_____	;Load #0002 into DX for
FFFD8	02	1FFEC	_____	;SCC CS* and indicating
FFFD7	BA	1FFEB	_____	;data to come instead of
			_____	;CW
FFFD6	05	1FFEB	_____	;Move the "A" at [40000]
FFFD5	8A	1FFEA	_____	;to AL
FFFD4	00	1FFEA	_____	;Load DI with 00 00
FFFD3	00	1FFE9	_____	;
FFFD2	BF	1FFE9	_____	;
FFFD1	D8	1FFE8	_____	;Move AX to DS reg
FFFD0	8E	1FFE8	_____	;
FFFCF	00	1FFE7	_____	;Move #4000 to AX
FFFCF	40	1FFE7	_____	;
FFFCF	B8	1FFE6	_____	;

The following code initializes the SCC registers for the proper baud rate and protocols.

FFFC0	EE	1FFE6	_____	;
FFFCB	03	1FFE5	_____	;Enable baud rate gen
FFFC9	B0	1FFE5	_____	;
FFFC8	EE	1FFE4	_____	;
FFFC7	0E	1FFE4	_____	;WR14
FFFC6	B0	1FFE3	_____	;
FFFC5	EE	1FFE3	_____	;
FFFC4	06	1FFE2	_____	;
FFFC3	B0	1FFE2	_____	;
FFFC2	EE	1FFE1	_____	;
FFFC1	0C	1FFE1	_____	;WR12
FFFC0	B0	1FFE0	_____	;
FFFBF	EE	1FFE0	_____	;
FFFBF	16	1FFDF	_____	;
FFFBF	B0	1FFDF	_____	;TRxC will have baud
FFFBF	EE	1FFDF	_____	rate out
FFFBF	EE	1FFDE	_____	;
FFFBF	0B	1FFDE	_____	;WR11
FFFBF	D0	1FFDD	_____	;
FFFBF	EE	1FFDD	_____	;Write WR5 with (AL)
FFFBF	68	1FFDD	_____	;
FFFBF	B0	1FFDC	_____	;Load AL with 68
			_____	;
			_____	8 bits/char
			_____	;
			_____	Tell WR0 that WR5 is
FFFBF	EE	1FFDB	_____	;
FFFBF	05	1FFDB	_____	next
FFFBF	B0	1FFDA	_____	;
			_____	Load AL with 05

FFFB4	EE	1FFDA	_____ ;Write WR4 with 4C (fm
FFFB3	4C	1FFD9	_____ ;AL); Load AL with 4C-
FFFB2	B0	1FFD9	_____ ;x16 Mode,2 stop bits
FFFB1	EE	1FFD8	_____ ;Load WR0 with 04 (fm AL)
FFFB0	04	1FFD8	_____ ;Load AL with 04--will
FFFAF	B0	1FFD7	_____ ;write Write Reg 4 (WR4)
FFFAE	00	1FFD7	_____ ;Load DX for CS* of the
FFFAF	00	1FFD6	_____ ;SCC to write a control
FFFAE	BA	1FFD6	_____ ;word (CW) to Write Reg 0
			_____ ;to tell the SCC which
			_____ ;register CW will be
			_____ ;written next

Load the character "A" into memory location [40000].

FFFAB	C1	1FFD5	_____ ;Write "A" to [DS + DI =
FFFAA	05	1FFD5	_____ ;40000]
FFFA9	C6	1FFD4	_____ ;
FFFA8	D8	1FFD4	_____ ;Move AX to DS
FFFA7	8E	1FFD3	_____ ;
FFFA6	40	1FFD3	_____ ;Move #4000 to AX
FFFA5	00	1FFD2	_____ ;
FFFA4	B8	1FFD2	_____ ;

81 bytes

APPENDIX J

LIST OF COMPONENTS

2 AM27C010--128K x 8 bit EPROM
8 MSM8128S-12--128K x 8 bit SRAM
3 CD54HC573F3A--Address latch (Octal D type latch)
2 CD54HC245F3--Data transceiver (Octal tri-state)
3 CD54138F3A--3 to 8 Decoder
1 MC74HC32N--quad 2 input OR gate
1 Z85C30--SCC serial communications controller
1 MD82C59A-5/B--Programmable interrupt controller
1 MD80C86-2/B--16 bit microprocessor
1 MD82C85/B--Static clock controller/generator
1 Xtal CTS MP150 15.000--15 MHz crystal (Have also used
4.0 MHz xtal)
1 MC7805C--5 volt voltage regulator
1 MM54HC161J/883C--Synchronous binary counter with
asynchronous clear
1 M82C53-5--Programmable interval timer
1 MC1488--quad line driver (+, - 9v)
1 MC1489A--quad line receiver(+5v)

1 82C55--programmable Peripheral interface

1 DB 25 P RS-232 connector
 Pin 2-Trans data Tx output
 Pin 3-Rcv data Rx input
 Pin 7-Sig Gnd Gnd common

1 SPDT Pushbutton switch

LIST OF REFERENCES

1. Hiser, James K., *Design of a Reliable Computing System for the Petite Amateur Navy Satellite (PANSAT)*, Master's Thesis, Naval Postgraduate School, Monterey, California, March 1989.
2. Sakoda, Daniel, Noble, Mike, and Paluszek, Steve(sic), "Preliminary Design of the Naval Postgraduate School Petite Amateur Navy Satellite (PANSAT) Electric Power and Communications Subsystems," briefing paper for the 4th Annual AIAA/Utah State University Conference on Small Satellites, August 28-31 1990.
3. DD Form 1721, Experiment Title: *Petite Amateur Navy Satellite*, Experiment No.: NPS-901, prepared 890130.
4. DD Form 1721, Experiment Title: *Petite Amateur Navy Satellite*, prepared 901210, Block 8b--Hardware Ready Flight Date; and Block 8c--Duration, Revision of DD Form 1721 with same title prepared 890130.
5. Sakoda, Daniel, "Petite Amateur Navy Satellite (PANSAT) A Proposal to the Defense Advance Research Projects Agency," proposal for research, by the Space Systems Academic group, Naval Postgraduate School, Monterey, California, October 1990.
6. Paluszek, Stephen E., *Spread Spectrum Communications for the Petite Amateur Navy Satellite (PANSAT)*, Master's Thesis, Naval Postgraduate School, Monterey, California, June 1990.
7. Couch, Leon W., *Digital and Analog Communication Systems*, 3rd Ed., Macmillan Publishing Company, 1990.
8. Noble, Michael A., *A Preliminary Design of the Electrical Power System for the Naval Postgraduate School's PANSAT*, Master's Thesis, Naval Postgraduate School, Monterey, California 1990.
9. *Get Away Special Small Self-Contained Payloads Experimenters Handbook*, National Aeronautics and Space Administration, 1984

10. Davidoff, Martin R., *The Satellite Experimenter's Handbook*, American Radio Relay League, Newington, Connecticut, 1985.
11. Siewiorek, Daniel P., and Swarz, Robert S., *The Theory and Practice of Reliable System Design*, Digital Equipment Corporation, 1982.
12. Wakerly, John F., *Digital Design Principles and Practices*, Prentice Hall, Englewood Cliffs, New Jersey, 1990.
13. *1988 Digital Product Data Book*, Harris Corporation, 1989.
14. *Reliability Handbook*, National Semiconductor Corporation, Santa Clara, California, 1987.
15. Fox, Terry L., *AX.25 Amateur Packet-Radio Link-Layer Protocol, Version 2.0*, American Radio Relay League, Newington, Connecticut, 1984.
16. Ward, J.W., and Price, H. E., "The UoSAT-2 Digital Communications Experiment," *Journal of the Institution of Electronic and Radio Engineers, (Australia)*, Vol. 57, No. 5(Supplement), pp. S163-S173, September, October 1987.
17. Bean, N.P., and others, "The UoSAT-C,D & E Technology Demonstration Satellites," *Proceedings of the Second Annual AIAA/Utah State University Conference on Small Satellites*, Utah State University, Logan, Utah, 1988.
18. Ohara, Moriyoshi, Masaya Fukasawa, and Youichi Kikukawa, "The FO-12 Mailbox System," *Proceedings of the AMSAT-NA Fifth Space Symposium and Annual Meeting*, pp. 57-61, American Radio Relay League, Newington, Connecticut, 1987.
19. Conversation between David Rigmaiden, Electronics technician and laboratory manager for Space Systems Academic group, NPS, and the Author, September 1990.
20. Horowitz, Paul, *The Art of Electronics*, 2nd Ed., Cambridge University Press, 1989.
21. Buchanan, James E., *CMOS/TTL Digital Systems Design*, McGraw Hill Publishing Company, 1990.
22. Lenk, John D., *Logic Designer's Manual*, Reston Publishing Company, 1977.

23. Conversation between David Rigmaiden, Electronics technician and laboratory manager for Space Systems Academic group, NPS, and the Author, October 1990.
24. Wakeman, Larry, "National's Process Enhancements Eliminate the CMOS SCR Latch-Up Problem in 54HC/74HC Logic," Application Note 339, *CMOS LOGIC DATABOOK*, National Semiconductor Corporation, pp. 2-112--2-119, 1988.
25. *RAD-HARD/HI-REL CICD DATA BOOK*, Harris Corporation, Custom Integrated Circuits Division, Revised June 1987.
26. *Z8000 Family Data Book*, Zilog, Inc., Campbell, California, pp. 222-252, November 1988.
27. Telephone Conversation between Mike Lewis, Zilog Corp. field service representative, and the Author, 5 December 1990.

INITIAL DISTRIBUTION LIST

1. Defense Technical Information Center Cameron Station Alexandria, Virginia 22304-6145	2
2. Library, Code 52 Naval Postgraduate School Monterey, California 93943-5002	2
3. Commander, 1101st Signal Brigade Bldg. 48, Fort McNair Washington, D.C. 20319-5050	1
4. LT John Quint SMC #1473 Naval Postgraduate School Monterey, California 93943	1
5. Kadri Hekimoglu DeGol Cadessi No = 1/5 Tandogan Ankara, Turkey	1
6. CPT Stephen M. Tobin	3
7. Professor Mitchell L. Cotton, Code EC/Cc Department of Electrical and Computer Engineering Naval Postgraduate School Monterey, California 93943	2
8. Professor Chin-Hwa Lee, Code EC/Le Department of Electrical and Computer Engineering Naval Postgraduate School Monterey, California 93943	1
9. Chairman, Code EC Department of Electrical and Computer Engineering Naval Postgraduate School Monterey, California 93943-5000	1
10. Chairman, Code SP Space Systems Academic Group Naval Postgraduate School Monterey, California 93943-5000	1